

# M29W640DT M29W640DB

64 Mbit (8Mb x8 or 4Mb x16, Boot Block) 3V Supply Flash Memory

**PRELIMINARY DATA** 

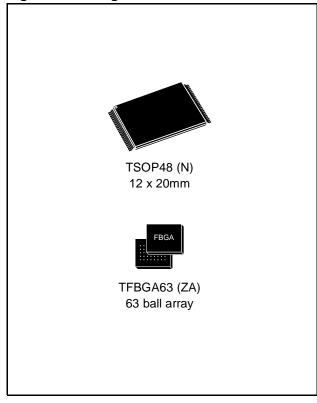
#### FEATURES SUMMARY

- SUPPLY VOLTAGE
  - V<sub>CC</sub> = 2.7V to 3.6V for Program, Erase, Read
  - V<sub>PP</sub> =12 V for Fast Program (optional)
- ACCESS TIME: 90 ns
- PROGRAMMING TIME
  - 10 µs per Byte/Word typical
  - Double Word Programming Option
- 135 MEMORY BLOCKS
  - 1 Boot Block and 7 Parameter Blocks,
     8 KBytes each (Top or Bottom Location)
  - 127 Main Blocks, 64 KBytes each
- PROGRAM/ERASE CONTROLLER
  - Embedded Byte/Word Program algorithms
- ERASE SUSPEND and RESUME MODES
  - Read and Program another Block during Erase Suspend
- UNLOCK BYPASS PROGRAM COMMAND
  - Faster Production/Batch Programming
- V<sub>PP</sub>/WP Pin for FAST PROGRAM and WRITE PROTECT
- TEMPORARY BLOCK UNPROTECTION MODE
- COMMON FLASH INTERFACE
  - 64-bit Security Code
- EXTENDED MEMORY BLOCK
  - Extra block used as security block or to store additional information
- LOW POWER CONSUMPTION
  - Standby and Automatic Standby
- 100,000 PROGRAM/ERASE CYCLES per BLOCK
- ELECTRONIC SIGNATURE

Downloaded from Elcodis.com electronic components distributor

- Manufacturer Code: 0020h
- Top Device Code M29W640DT: 22DEh
- Bottom Device Code M29W640DB: 22DFh

# Figure 1. Packages



December 2003 1/50

# M29W640DT, M29W640DB

# **TABLE OF CONTENTS**

FEATURES SUMMARY	1
Figure 1. Packages	1
SUMMARY DESCRIPTION	5
Figure 2. Logic Diagram	5
Table 1. Signal Names	5
Figure 3. TSOP Connections	6
Figure 4. TFBGA Connections (Top view through package)	7
SIGNAL DESCRIPTIONS	8
Address Inputs (A0-A21)	8
Data Inputs/Outputs (DQ0-DQ7)	8
Data Inputs/Outputs (DQ8-DQ14)	8
Data Input/Output or Address Input (DQ15A-1)	8
Chip Enable (E)	
Output Enable (G)	
Write Enable $(\overline{W})$	
$V_{PP}/W$ rite Protect ( $V_{PP}/\overline{WP}$ )	
Reset/Block Temporary Unprotect (RP)	
Ready/Busy Output (RB)	
Byte/Word Organization Select (BYTE)	
V <sub>CC</sub> Supply Voltage (2.7V to 3.6V)	
V <sub>SS</sub> Ground	9
BUS OPERATIONS	10
Bus Read	10
Bus Write	
Output Disable	
Standby	
Automatic Standby	10
Special Bus Operations	10
Electronic Signature	10
Block Protect and Chip Unprotect	10
Table 2. Bus Operations, BYTE = V <sub>IL</sub>	11
Table 3. Bus Operations, BYTE = V <sub>IH</sub>	11
COMMAND INTERFACE	12
Read/Reset Command	12
Auto Select Command	
Read CFI Query Command	12
Program Command	12
Fast Program Commands	12
Quadruple Byte Program Command	13
Double Word Program Command	13

	Unlock Bypass Command	. 13
	Unlock Bypass Program Command	. 13
	Unlock Bypass Reset Command	. 13
	Chip Erase Command	. 13
	Block Erase Command	. 14
	Erase Suspend Command	
	Erase Resume Command	
	Enter Extended Block Command	
	Exit Extended Block Command	
	Block Protect and Chip Unprotect Commands	. 15
	Table 4. Commands, 16-bit mode, BYTE = V <sub>IH</sub>	. 16
	Table 5. Commands, 8-bit mode, $\overline{BYTE} = V_{IL}$	
	Table 6. Program, Erase Times and Program, Erase Endurance Cycles	
ST	ATUS REGISTER	. 18
	Data Polling Bit (DQ7)	. 18
	Toggle Bit (DQ6)	
	Error Bit (DQ5)	
	Erase Timer Bit (DQ3).	
	Alternative Toggle Bit (DQ2)	
	Table 7. Status Register Bits	
	Figure 5. Data Polling Flowchart	
	Figure 6. Data Toggle Flowchart	
MΑ	XIMUM RATING	. 20
MΑ	Table 8. Absolute Maximum Ratings	
	Table 8. Absolute Maximum Ratings	. 20
		. 20
	Table 8. Absolute Maximum Ratings	. 20 <b>. 21</b>
	Table 8. Absolute Maximum Ratings	. 20 <b>. 21</b> . 21
	Table 8. Absolute Maximum Ratings	. 20 . <b>21</b> . 21
	Table 8. Absolute Maximum Ratings	. 20 . 21 . 21 . 21
	Table 8. Absolute Maximum Ratings	. 20 . 21 . 21 . 21 . 21
	Table 8. Absolute Maximum Ratings	. 20 . 21 . 21 . 21 . 21 . 22
	Table 8. Absolute Maximum Ratings  and AC PARAMETERS  Table 9. Operating and AC Measurement Conditions  Figure 7. AC Measurement I/O Waveform  Figure 8. AC Measurement Load Circuit  Table 10. Device Capacitance  Table 11. DC Characteristics	. 20 . 21 . 21 . 21 . 21 . 22 . 23
	Table 8. Absolute Maximum Ratings.  and AC PARAMETERS.  Table 9. Operating and AC Measurement Conditions.  Figure 7. AC Measurement I/O Waveform.  Figure 8. AC Measurement Load Circuit.  Table 10. Device Capacitance.  Table 11. DC Characteristics.  Figure 9. Read Mode AC Waveforms.	. 20 . 21 . 21 . 21 . 21 . 22 . 23 . 23
	Table 8. Absolute Maximum Ratings.  and AC PARAMETERS.  Table 9. Operating and AC Measurement Conditions.  Figure 7. AC Measurement I/O Waveform.  Figure 8. AC Measurement Load Circuit.  Table 10. Device Capacitance.  Table 11. DC Characteristics.  Figure 9. Read Mode AC Waveforms.  Table 12. Read AC Characteristics.	. 20 . 21 . 21 . 21 . 21 . 21 . 22 . 23 . 23
	Table 8. Absolute Maximum Ratings.  and AC PARAMETERS.  Table 9. Operating and AC Measurement Conditions.  Figure 7. AC Measurement I/O Waveform.  Figure 8. AC Measurement Load Circuit.  Table 10. Device Capacitance.  Table 11. DC Characteristics.  Figure 9. Read Mode AC Waveforms.  Table 12. Read AC Characteristics  Figure 10.Write AC Waveforms, Write Enable Controlled.	. 20 . 21 . 21 . 21 . 21 . 21 . 22 . 23 . 23 . 24
	Table 8. Absolute Maximum Ratings	. 20 . 21 . 21 . 21 . 21 . 21 . 23 . 23 . 23 . 24 . 24
	Table 8. Absolute Maximum Ratings	. 20 . 21 . 21 . 21 . 21 . 21 . 22 . 23 . 23 . 24 . 25
	Table 8. Absolute Maximum Ratings.  and AC PARAMETERS  Table 9. Operating and AC Measurement Conditions.  Figure 7. AC Measurement I/O Waveform.  Figure 8. AC Measurement Load Circuit.  Table 10. Device Capacitance.  Table 11. DC Characteristics.  Figure 9. Read Mode AC Waveforms.  Table 12. Read AC Characteristics  Figure 10.Write AC Waveforms, Write Enable Controlled.  Table 13. Write AC Characteristics, Write Enable Controlled  Figure 11.Write AC Waveforms, Chip Enable Controlled.  Table 14. Write AC Characteristics, Chip Enable Controlled.	. 20 . 21 . 21 . 21 . 21 . 21 . 22 . 23 . 23 . 24 . 25 . 25
	Table 8. Absolute Maximum Ratings.  and AC PARAMETERS  Table 9. Operating and AC Measurement Conditions.  Figure 7. AC Measurement I/O Waveform.  Figure 8. AC Measurement Load Circuit.  Table 10. Device Capacitance.  Table 11. DC Characteristics.  Figure 9. Read Mode AC Waveforms.  Table 12. Read AC Characteristics  Figure 10.Write AC Waveforms, Write Enable Controlled.  Table 13. Write AC Characteristics, Write Enable Controlled  Figure 11.Write AC Waveforms, Chip Enable Controlled.  Table 14. Write AC Characteristics, Chip Enable Controlled.  Figure 12.Reset/Block Temporary Unprotect AC Waveforms.	. 20 . 21 . 21 . 21 . 21 . 21 . 22 . 23 . 23 . 24 . 25 . 25 . 26
DC	Table 8. Absolute Maximum Ratings.  and AC PARAMETERS  Table 9. Operating and AC Measurement Conditions.  Figure 7. AC Measurement I/O Waveform.  Figure 8. AC Measurement Load Circuit.  Table 10. Device Capacitance.  Table 11. DC Characteristics.  Figure 9. Read Mode AC Waveforms.  Table 12. Read AC Characteristics  Figure 10.Write AC Waveforms, Write Enable Controlled.  Table 13. Write AC Characteristics, Write Enable Controlled.  Figure 11.Write AC Waveforms, Chip Enable Controlled.  Figure 14. Write AC Characteristics, Chip Enable Controlled.  Figure 12.Reset/Block Temporary Unprotect AC Waveforms.  Table 15. Reset/Block Temporary Unprotect AC Characteristics  Figure 13.Accelerated Program Timing Waveforms	. 20 . 21 . 21 . 21 . 21 . 23 . 23 . 24 . 25 . 26 . 26
DC	Table 8. Absolute Maximum Ratings.  and AC PARAMETERS  Table 9. Operating and AC Measurement Conditions.  Figure 7. AC Measurement I/O Waveform.  Figure 8. AC Measurement Load Circuit.  Table 10. Device Capacitance.  Table 11. DC Characteristics.  Figure 9. Read Mode AC Waveforms.  Table 12. Read AC Characteristics.  Figure 10.Write AC Waveforms, Write Enable Controlled.  Table 13. Write AC Characteristics, Write Enable Controlled.  Figure 11.Write AC Waveforms, Chip Enable Controlled.  Table 14. Write AC Characteristics, Chip Enable Controlled.  Figure 12.Reset/Block Temporary Unprotect AC Waveforms.  Table 15. Reset/Block Temporary Unprotect AC Characteristics.	. 20 . 21 . 21 . 21 . 21 . 23 . 23 . 24 . 25 . 26 . 26
DC	Table 8. Absolute Maximum Ratings.  and AC PARAMETERS  Table 9. Operating and AC Measurement Conditions.  Figure 7. AC Measurement I/O Waveform.  Figure 8. AC Measurement Load Circuit.  Table 10. Device Capacitance.  Table 11. DC Characteristics.  Figure 9. Read Mode AC Waveforms.  Table 12. Read AC Characteristics  Figure 10.Write AC Waveforms, Write Enable Controlled.  Table 13. Write AC Characteristics, Write Enable Controlled.  Figure 11.Write AC Waveforms, Chip Enable Controlled.  Figure 14. Write AC Characteristics, Chip Enable Controlled.  Figure 12.Reset/Block Temporary Unprotect AC Waveforms.  Table 15. Reset/Block Temporary Unprotect AC Characteristics  Figure 13.Accelerated Program Timing Waveforms	. 20 . 21 . 21 . 21 . 21 . 21 . 23 . 23 . 24 . 25 . 26 . 26 . 26
DC	Table 8. Absolute Maximum Ratings.  and AC PARAMETERS  Table 9. Operating and AC Measurement Conditions.  Figure 7. AC Measurement I/O Waveform  Figure 8. AC Measurement Load Circuit.  Table 10. Device Capacitance.  Table 11. DC Characteristics.  Figure 9. Read Mode AC Waveforms.  Table 12. Read AC Characteristics  Figure 10.Write AC Waveforms, Write Enable Controlled.  Table 13. Write AC Characteristics, Write Enable Controlled  Figure 11.Write AC Waveforms, Chip Enable Controlled  Table 14. Write AC Characteristics, Chip Enable Controlled.  Figure 12.Reset/Block Temporary Unprotect AC Waveforms.  Table 15. Reset/Block Temporary Unprotect AC Characteristics  Figure 13.Accelerated Program Timing Waveforms  CKAGE MECHANICAL	. 20 . 21 . 21 . 21 . 21 . 23 . 23 . 24 . 25 . 25 . 26 . 26



# M29W640DT, M29W640DB

	Figure 15.TFBGA63 7x11mm - 6x8 active ball array, 0.8mm pitch, Package Outline	. 28
	Table 17. TFBGA63 7x11mm - 6x8 active ball array, 0.8mm pitch, Package Mechanical Data	. 28
PΑ	ART NUMBERING	. 29
	Table 18. Ordering Information Scheme	. 29
ΑF	PPENDIX A.BLOCK ADDRESSES	. 30
	Table 19. Top Boot Block Addresses, M29W640DT	. 30
	Table 20. Bottom Boot Block Addresses, M29W640DB	. 34
ΑF	PPENDIX B.COMMON FLASH INTERFACE (CFI)	. 39
	Table 21. Query Structure Overview	. 39
	Table 22. CFI Query Identification String	. 39
	Table 23. CFI Query System Interface Information	. 40
	Table 24. Device Geometry Definition	. 41
	Table 25. Primary Algorithm-Specific Extended Query Table	. 42
	Table 26. Security Code Area	. 42
ΑF	PPENDIX C.EXTENDED MEMORY BLOCK	. 43
	Factory Locked Extended Block	. 43
	Customer Lockable Extended Block	. 43
	Table 27. Extended Block Address and Data	. 43
ΑF	PPENDIX D.BLOCK PROTECTION	. 44
	Programmer Technique	. 44
	In-System Technique	
	Table 28. Programmer Technique Bus Operations, BYTE = V <sub>IH</sub> or V <sub>IL</sub>	
	Figure 16.Programmer Equipment Group Protect Flowchart	
	Figure 17.Programmer Equipment Chip Unprotect Flowchart	
	Figure 18.In-System Equipment Group Protect Flowchart	
	Figure 19.In-System Equipment Chip Unprotect Flowchart	. 48
RE	EVISION HISTORY	. 49
	Table 29. Document Revision History	. 49

#### SUMMARY DESCRIPTION

The M29W640D is a 64 Mbit (8Mb x8 or 4Mb x16) non-volatile memory that can be read, erased and reprogrammed. These operations can be performed using a single low voltage (2.7 to 3.6V) supply. On power-up the memory defaults to its Read mode.

The memory is divided into blocks that can be erased independently so it is possible to preserve valid data while old data is erased. Blocks can be protected in units of 256 KByte (generally groups of four 64 KByte blocks), to prevent accidental Program or Erase commands from modifying the memory. Program and Erase commands are written to the Command Interface of the memory. An on-chip Program/Erase Controller simplifies the process of programming or erasing the memory by taking care of all of the special operations that are required to update the memory contents. The end of a program or erase operation can be detected and any error conditions identified. The command set required to control the memory is consistent with JEDEC standards.

The device features an asymmetrical blocked architecture. The device has an array of 135 blocks:

- 8 Parameters Blocks of 8 KBytes each (or 4 KWords each)
- 127 Main Blocks of 64 KBytes each (or 32 KWords each)

M29W640DT has the Parameter Blocks at the top of the memory address space while the M29W640DB locates the Parameter Blocks starting from the bottom.

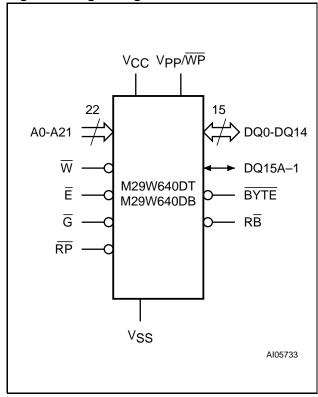
The M29W640D has an extra block, the Extended Block, (of 32 KWords in x16 mode or of 64 KBytes in x8 mode) that can be accessed using a dedicated command. The Extended Block can be protected and so is useful for storing security information. However the protection is not reversible, once protected the protection cannot be undone.

Chip Enable, Output Enable and Write Enable signals control the bus operation of the memory. They allow simple connection to most microprocessors, often without additional logic.

The V<sub>PP</sub>/WP signal is used to enable faster programming of the device, enabling double word programming. If this signal is held at V<sub>SS</sub>, the boot block, and its adjacent parameter block, are protected from program and erase operations.

The memory is delivered with all the bits erased (set to 1).

Figure 2. Logic Diagram



**Table 1. Signal Names** 

A0-A21	Address Inputs
DQ0-DQ7	Data Inputs/Outputs
DQ8-DQ14	Data Inputs/Outputs
DQ15A-1 (or DQ15)	Data Input/Output or Address Input (or Data Input/Output)
Ē	Chip Enable
G	Output Enable
$\overline{W}$	Write Enable
RP	Reset/Block Temporary Unprotect
R₿	Ready/Busy Output
BYTE	Byte/Word Organization Select
Vcc	Supply Voltage
V <sub>PP</sub> /WP	Supply Voltage for Fast Program (optional) or Write Protect
V <sub>SS</sub>	Ground
NC	Not Connected Internally



Figure 3. TSOP Connections

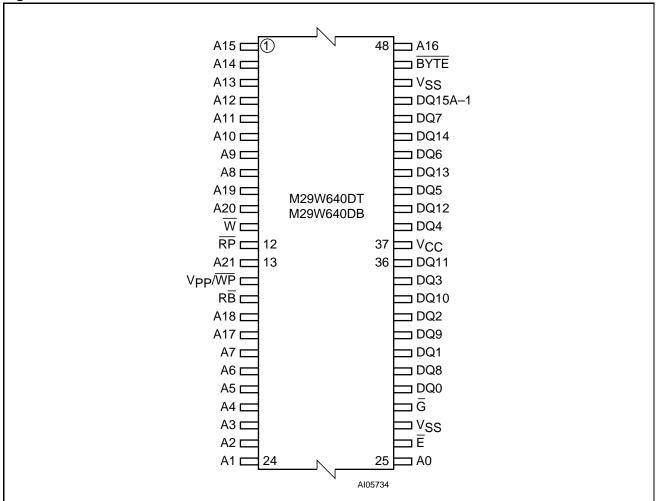
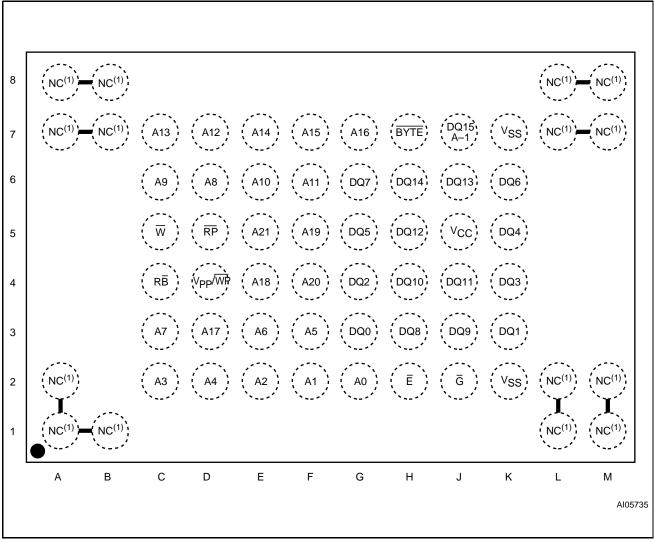


Figure 4. TFBGA Connections (Top view through package)



Note: 1. Balls are shorted together via the substrate but not connected to the die.

#### SIGNAL DESCRIPTIONS

See Figure 2, Logic Diagram, and Table 1, Signal Names, for a brief overview of the signals connected to this device.

Address Inputs (A0-A21). The Address Inputs select the cells in the memory array to access during Bus Read operations. During Bus Write operations they control the commands sent to the Command Interface of the Program/Erase Controller.

**Data Inputs/Outputs (DQ0-DQ7).** The Data I/O outputs the data stored at the selected address during a Bus Read operation. During Bus Write operations they represent the commands sent to the Command Interface of the Program/Erase Controller.

Data Inputs/Outputs (DQ8-DQ14). The Data I/O outputs the data stored at the selected address during a Bus Read operation when BYTE is High,  $V_{IH}$ . When BYTE is Low,  $V_{IL}$ , these pins are not used and are high impedance. During Bus Write operations the Command Register does not use these bits. When reading the Status Register these bits should be ignored.

#### Data Input/Output or Address Input (DQ15A-1).

When BYTE is High, V<sub>IH</sub>, this pin behaves as a Data Input/Output pin (as DQ8-DQ14). When BYTE is Low, V<sub>IL</sub>, this pin behaves as an address pin; DQ15A-1 Low will select the LSB of the addressed Word, DQ15A-1 High will select the MSB. Throughout the text consider references to the Data Input/Output to include this pin when BYTE is High and references to the Address Inputs to include this pin when BYTE is Low except when stated explicitly otherwise.

**Chip Enable (E).** The Chip Enable, E, activates the memory, allowing Bus Read and Bus Write operations to be performed. When Chip Enable is High,  $V_{IH}$ , all other pins are ignored.

**Output Enable (G).** The Output Enable, G, controls the Bus Read operation of the memory.

**Write Enable (W).** The Write Enable, W, controls the Bus Write operation of the memory's Command Interface.

**VPP/Write Protect (VPP/WP).** The VPP/Write Protect pin provides two functions. The VPP function allows the memory to use an external high voltage power supply to reduce the time required for Unlock Bypass Program operations. The Write Protect function provides a hardware method of protecting the two outermost boot blocks. The VPP/Write Protect pin must not be left floating or unconnected.

When V<sub>PP</sub>/Write Protect is Low, V<sub>IL</sub>, the memory protects the two outermost boot blocks; Program

and Erase operations in this block are ignored while V<sub>PP</sub>/Write Protect is Low.

When V<sub>PP</sub>/Write Protect is High, V<sub>IH</sub>, the memory reverts to the previous protection status of the two outermost boot blocks. Program and Erase operations can now modify the data in the two outermost boot blocks unless the block is protected using Block Protection.

When  $V_{PP}/W$ rite Protect is raised to  $V_{PP}$  the memory automatically enters the Unlock Bypass mode. When  $V_{PP}/W$ rite Protect returns to  $V_{IH}$  or  $V_{IL}$  normal operation resumes. During Unlock Bypass Program operations the memory draws  $I_{PP}$  from the pin to supply the programming circuits. See the description of the Unlock Bypass command in the Command Interface section. The transitions from  $V_{IH}$  to  $V_{PP}$  and from  $V_{PP}$  to  $V_{IH}$  must be slower than  $t_{VHVPP}$ , see Figure 13.

Never raise V<sub>PP</sub>/Write Protect to V<sub>PP</sub> from any mode except Read mode, otherwise the memory may be left in an indeterminate state.

A  $0.1\mu F$  capacitor should be connected between the  $V_{PP}/W$ rite Protect pin and the  $V_{SS}$  Ground pin to decouple the current surges from the power supply. The PCB track widths must be sufficient to carry the currents required during Unlock Bypass Program,  $I_{PP}$ .

Reset/Block Temporary Unprotect (RP). The Reset/Block Temporary Unprotect pin can be used to apply a Hardware Reset to the memory or to temporarily unprotect all Blocks that have been protected.

Note that if  $V_{PP}/WP$  is at  $V_{IL}$ , then the two outermost boot blocks will remain protected even if RP is at  $V_{ID}$ .

A Hardware Reset is achieved by holding Reset/Block Temporary Unprotect Low,  $V_{IL}$ , for at least  $t_{PLPX}$ . After Reset/Block Temporary Unprotect goes High,  $V_{IH}$ , the memory will be ready for Bus Read and Bus Write operations after  $t_{PHEL}$  or  $t_{RHEL}$ , whichever occurs last. See the Ready/Busy Output section, Table 15 and Figure 12, Reset/Block Temporary Unprotect AC Characteristics, for more details.

Holding RP at  $V_{ID}$  will temporarily unprotect the protected Blocks in the memory. Program and Erase operations on all blocks will be possible. The transition from  $V_{IH}$  to  $V_{ID}$  must be slower than  $t_{PHPHH}$ .

**Ready/Busy Output (RB).** The Ready/Busy pin is an open-drain output that can be used to identify when the device is performing a Program or Erase operation. During Program or Erase operations Ready/Busy is Low, V<sub>OL</sub>. Ready/Busy is high-impedance during Read mode, Auto Select mode and Erase Suspend mode.

After a Hardware Reset, Bus Read and Bus Write operations cannot begin until Ready/Busy becomes high-impedance. See Table 15 and Figure 12, Reset/Block Temporary Unprotect AC Characteristics.

The use of an open-drain output allows the Ready/ Busy pins from several memories to be connected to a single pull-up resistor. A Low will then indicate that one, or more, of the memories is busy.

Byte/Word Organization Select (BYTE). The Byte/Word Organization Select pin is used to switch between the x8 and x16 Bus modes of the memory. When Byte/Word Organization Select is Low,  $V_{IL}$ , the memory is in x8 mode, when it is High,  $V_{IH}$ , the memory is in x16 mode.

 $V_{CC}$  Supply Voltage (2.7V to 3.6V).  $V_{CC}$  provides the power supply for all operations (Read, Program and Erase).

The Command Interface is disabled when the  $V_{CC}$  Supply Voltage is less than the Lockout Voltage,  $V_{LKO}$ . This prevents Bus Write operations from accidentally damaging the data during power up, power down and power surges. If the Program/ Erase Controller is programming or erasing during this time then the operation aborts and the memory contents being altered will be invalid.

A  $0.1\mu F$  capacitor should be connected between the  $V_{CC}$  Supply Voltage pin and the  $V_{SS}$  Ground pin to decouple the current surges from the power supply. The PCB track widths must be sufficient to carry the currents required during Program and Erase operations,  $I_{CC3}$ .

 $V_{SS}$  Ground.  $V_{SS}$  is the reference for all voltage measurements. The device features two  $V_{SS}$  pins which must be both connected to the system ground.

#### **BUS OPERATIONS**

There are five standard bus operations that control the device. These are Bus Read, Bus Write, Output Disable, Standby and Automatic Standby. See Table 2 and Table 3, Bus Operations, for a summary. Typically glitches of less than 5ns on Chip Enable or Write Enable are ignored by the memory and do not affect bus operations.

**Bus Read.** Bus Read operations read from the memory cells, or specific registers in the Command Interface. A valid Bus Read operation involves setting the desired address on the Address Inputs, applying a Low signal,  $V_{IL}$ , to Chip Enable and Output Enable and keeping Write Enable High,  $V_{IH}$ . The Data Inputs/Outputs will output the value, see Figure 9, Read Mode AC Waveforms, and Table 12, Read AC Characteristics, for details of when the output becomes valid.

**Bus Write.** Bus Write operations write to the Command Interface. A valid Bus Write operation begins by setting the desired address on the Address Inputs. The Address Inputs are latched by the Command Interface on the falling edge of Chip Enable or Write Enable, whichever occurs last. The Data Inputs/Outputs are latched by the Command Interface on the rising edge of Chip Enable or Write Enable, whichever occurs first. Output Enable must remain High, V<sub>IH</sub>, during the whole Bus Write operation. See Figure 10 and Figure 11, Write AC Waveforms, and Table 13 and Table 14, Write AC Characteristics, for details of the timing requirements.

**Output Disable.** The Data Inputs/Outputs are in the high impedance state when Output Enable is High,  $V_{IH}$ .

**Standby.** When Chip Enable is High, V<sub>IH</sub>, the memory enters Standby mode and the Data Inputs/Outputs pins are placed in the high-impedance state. To reduce the Supply Current to the Standby Supply Current, I<sub>CC2</sub>, Chip Enable should

be held within  $V_{CC} \pm 0.2V$ . For the Standby current level see Table 11, DC Characteristics.

During program or erase operations the memory will continue to use the Program/Erase Supply Current,  $I_{CC3}$ , for Program or Erase operations until the operation completes.

**Automatic Standby.** If CMOS levels ( $V_{CC}\pm0.2V$ ) are used to drive the bus and the bus is inactive for 300ns or more the memory enters Automatic Standby where the internal Supply Current is reduced to the Standby Supply Current,  $I_{CC2}$ . The Data Inputs/Outputs will still output data if a Bus Read operation is in progress.

# **Special Bus Operations**

Additional bus operations can be performed to read the Electronic Signature and also to apply and remove Block Protection. These bus operations are intended for use by programming equipment and are not usually used in applications. They require  $V_{\text{ID}}$  to be applied to some pins.

**Electronic Signature.** The memory has two codes, the manufacturer code and the device code, that can be read to identify the memory. These codes can be read by applying the signals listed in Table 2 and Table 3, Bus Operations.

**Block Protect and Chip Unprotect.** Groups of blocks can be protected against accidental Program or Erase. The Protection Groups are shown in Appendix A, Table 19 and Table 20, Block Addresses. The whole chip can be unprotected to allow the data inside the blocks to be changed.

The  $V_{PP}$ /Write Protect pin can be used to protect the two outermost boot blocks. When  $V_{PP}$ /Write Protect is at  $V_{IL}$  the two outermost boot blocks are protected and remain protected regardless of the Block Protection Status or the Reset/Block Temporary Unprotect pin status.

Block Protect and Chip Unprotect operations are described in Appendix D.

Table 2. Bus Operations,  $\overline{\text{BYTE}} = V_{\text{IL}}$ 

Operation	Ē	G	$\overline{\mathbf{w}}$	Address Inputs	Data Inputs/Outputs			
Operation	-	G	, vv	DQ15A-1, A0-A21	DQ14-DQ8	DQ7-DQ0		
Bus Read	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	Cell Address	Hi-Z	Data Output		
Bus Write	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	Command Address	Hi-Z	Data Input		
Output Disable	Х	V <sub>IH</sub>	V <sub>IH</sub>	Х	Hi-Z	Hi-Z		
Standby	$V_{IH}$	Х	Х	Х	Hi-Z	Hi-Z		
Read Manufacturer Code	VIL	VIL	V <sub>IH</sub>	$\label{eq:A0} \begin{split} A0 &= V_{IL},  A1 = V_{IL},  A9 = V_{ID}, \\ \text{Others } V_{IL} \text{ or } V_{IH} \end{split}$	Hi-Z	20h		
Read Device Code	VIL	VIL	V <sub>IH</sub>	$A0 = V_{IH}$ , $A1 = V_{IL}$ , $A9 = V_{ID}$ , Others $V_{IL}$ or $V_{IH}$	Hi-Z	DEh (M29W640DT) DFh (M29W640DB)		
Extended Memory	V	Vu	V	A0 = V <sub>IH</sub> , A1 = V <sub>IH</sub> , A6 = V <sub>IL</sub> ,	Hi-Z	M29W640DT 98h (factory locked) 18h (not factory locked)		
Block Verify Code	, I All I All I All I		A9 = V <sub>ID</sub> , Others V <sub>IL</sub> or V <sub>IH</sub>	ΠΙ-Ζ	M29W640DB 88h (factory locked) 08h (not factory locked)			

Note:  $X = V_{IL}$  or  $V_{IH}$ .

Table 3. Bus Operations,  $\overline{\text{BYTE}} = V_{\text{IH}}$ 

Operation	Ē	G	$\overline{w}$	Address Inputs A0-A21	Data Inputs/Outputs DQ15A-1, DQ14-DQ0
Bus Read	VIL	VIL	V <sub>IH</sub>	Cell Address	Data Output
Bus Write	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	Command Address	Data Input
Output Disable	Х	V <sub>IH</sub>	V <sub>IH</sub>	Х	Hi-Z
Standby	VIH	Х	Х	Х	Hi-Z
Read Manufacturer Code	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	$\label{eq:A0} \begin{split} A0 &= V_{IL}, \ A1 = V_{IL}, \ A9 = V_{ID}, \\ Others \ V_{IL} \ or \ V_{IH} \end{split}$	0020h
Read Device Code	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	$\label{eq:A0} \begin{split} A0 &= V_{IH}, \ A1 = V_{IL}, \ A9 = V_{ID}, \\ Others \ V_{IL} \ or \ V_{IH} \end{split}$	22DEh (M29W640DT) 22DFh (M29W640DB)
Extended Memory	V	V	A0 - Vu. A1 - Vu. A6 - Vu		M29W640DT 98h (factory locked) 18h (not factory locked)
Block Verify Code	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	A9 = $V_{ID}$ , Others $V_{IL}$ or $V_{IH}$	M29W640DB 88h (factory locked) 08h (not factory locked)

Note:  $X = V_{IL}$  or  $V_{IH}$ .



#### **COMMAND INTERFACE**

All Bus Write operations to the memory are interpreted by the Command Interface. Commands consist of one or more sequential Bus Write operations. Failure to observe a valid sequence of Bus Write operations will result in the memory returning to Read mode. The long command sequences are imposed to maximize data security.

The address used for the commands changes depending on whether the memory is in 16-bit or 8-bit mode. See either Table 4, or Table 5, depending on the configuration that is being used, for a summary of the commands.

#### Read/Reset Command.

The Read/Reset command returns the memory to its Read mode. It also resets the errors in the Status Register. Either one or three Bus Write operations can be used to issue the Read/Reset command.

The Read/Reset command can be issued, between Bus Write cycles before the start of a program or erase operation, to return the device to read mode. If the Read/Reset command is issued during the timeout of a Block Erase operation then the memory will take up to 10µs to abort. During the abort period no valid data can be read from the memory. The Read/Reset command will not abort an Erase operation when issued while in Erase Suspend.

#### Auto Select Command.

The Auto Select command is used to read the Manufacturer Code, the Device Code, the Block Protection Status and the Extended Memory Block Verify Code. Three consecutive Bus Write operations are required to issue the Auto Select command. Once the Auto Select command is issued the memory remains in Auto Select mode until a Read/Reset command is issued. Read CFI Query and Read/Reset commands are accepted in Auto Select mode, all other commands are ignored.

In Auto Select mode the Manufacturer Code can be read using a Bus Read operation with  $A0 = V_{IL}$  and  $A1 = V_{IL}$ . The other address bits may be set to either  $V_{IL}$  or  $V_{IH}$ . The Manufacturer Code for ST-Microelectronics is 0020h.

The Device Code can be read using a Bus Read operation with  $A0 = V_{IH}$  and  $A1 = V_{IL}$ . The other address bits may be set to either  $V_{IL}$  or  $V_{IH}$ . The Device Code for the M29W640DT is 22DEh and for the M29W640DB is 22DFh.

The Block Protection Status of each block can be read using a Bus Read operation with  $A0 = V_{IL}$ ,  $A1 = V_{IH}$ , and A12-A21 specifying the address of the block. The other address bits may be set to either  $V_{IL}$  or  $V_{IH}$ . If the addressed block is protected then 01h is output on Data Inputs/Outputs DQ0-DQ7, otherwise 00h is output.

#### **Read CFI Query Command**

The Read CFI Query Command is used to read data from the Common Flash Interface (CFI) Memory Area. This command is valid when the device is in the Read Array mode, or when the device is in Autoselected mode.

One Bus Write cycle is required to issue the Read CFI Query Command. Once the command is issued subsequent Bus Read operations read from the Common Flash Interface Memory Area.

The Read/Reset command must be issued to return the device to the previous mode (the Read Array mode or Autoselected mode). A second Read/Reset command would be needed if the device is to be put in the Read Array mode from Autoselected mode.

See Appendix B, Table 21 to Table 26 for details on the information contained in the Common Flash Interface (CFI) memory area.

# **Program Command.**

The Program command can be used to program a value to one address in the memory array at a time. The command requires four Bus Write operations, the final write operation latches the address and data, and starts the Program/Erase Controller.

If the address falls in a protected block then the Program command is ignored, the data remains unchanged. The Status Register is never read and no error condition is given.

During the program operation the memory will ignore all commands. It is not possible to issue any command to abort or pause the operation. Typical program times are given in Table 6. Bus Read operations during the program operation will output the Status Register on the Data Inputs/Outputs. See the section on the Status Register for more details.

After the program operation has completed the memory will return to the Read mode, unless an error has occurred. When an error occurs the memory will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read mode.

Note that the Program command cannot change a bit set at '0' back to '1'. One of the Erase Commands must be used to set all the bits in a block or in the whole memory from '0' to '1'.

# **Fast Program Commands**

There are two Fast Program commands available to improve the programming throughput, by writing several adjacent words or bytes in parallel. The Quadruple Byte Program command is available for x8 operations, while the Double Word Program command is available for x16 operations.

**Quadruple Byte Program Command.** The Quadruple Byte Program command is used to write a page of four adjacent Bytes in parallel. The four bytes must differ only for addresses A0, DQ15A-1. Five bus write cycles are necessary to issue the Quadruple Byte Program command.

- The first bus cycle sets up the Quadruple Byte Program Command.
- The second bus cycle latches the Address and the Data of the first byte to be written.
- The third bus cycle latches the Address and the Data of the second byte to be written.
- The fourth bus cycle latches the Address and the Data of the third byte to be written.
- The fifth bus cycle latches the Address and the Data of the fourth byte to be written and starts the Program/Erase Controller.

#### **Double Word Program Command.**

The Double Word Program command is used to write a page of two adjacent words in parallel. The two words must differ only for the address A0. Programming should not be attempted when  $V_{PP}$  is not at  $V_{PPH}$ .

Three bus write cycles are necessary to issue the Double Word Program command.

- The first bus cycle sets up the Double Word Program Command.
- The second bus cycle latches the Address and the Data of the first word to be written.
- The third bus cycle latches the Address and the Data of the second word to be written and starts the Program/Erase Controller.

After the program operation has completed the memory will return to the Read mode, unless an error has occurred. When an error occurs Bus Read operations will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read mode.

Note that the Fast Program commands cannot change a bit set at '0' back to '1'. One of the Erase Commands must be used to set all the bits in a block or in the whole memory from '0' to '1'.

Typical Program times are given in Table 6, Program, Erase Times and Program, Erase Endurance Cycles.

# **Unlock Bypass Command.**

The Unlock Bypass command is used in conjunction with the Unlock Bypass Program command to program the memory faster than with the standard program commands. When the cycle time to the device is long, considerable time saving can be made by using these commands. Three Bus Write

operations are required to issue the Unlock Bypass command.

Once the Unlock Bypass command has been issued the memory will only accept the Unlock Bypass Program command and the Unlock Bypass Reset command. The memory can be read as if in Read mode.

When V<sub>PP</sub> is applied to the V<sub>PP</sub>/Write Protect pin the memory automatically enters the Unlock Bypass mode and the Unlock Bypass Program command can be issued immediately.

#### **Unlock Bypass Program Command.**

The Unlock Bypass command is used in conjunction with the Unlock Bypass Program command to program the memory. When the cycle time to the device is long, considerable time saving can be made by using these commands. Three Bus Write operations are required to issue the Unlock Bypass command.

Once the Unlock Bypass command has been issued the memory will only accept the Unlock Bypass Program command and the Unlock Bypass Reset command. The memory can be read as if in Read mode.

The memory offers accelerated program operations through the  $V_{PP}/W$ rite Protect pin. When the system asserts  $V_{PP}$  on the  $V_{PP}/W$ rite Protect pin, the memory automatically enters the Unlock Bypass mode. The system may then write the two-cycle Unlock Bypass program command sequence. The memory uses the higher voltage on the  $V_{PP}/W$ rite Protect pin, to accelerate the Unlock Bypass Program operation.

Never raise V<sub>PP</sub>/Write Protect to V<sub>PP</sub> from any mode except Read mode, otherwise the memory may be left in an indeterminate state.

#### Unlock Bypass Reset Command.

The Unlock Bypass Reset command can be used to return to Read/Reset mode from Unlock Bypass Mode. Two Bus Write operations are required to issue the Unlock Bypass Reset command. Read/Reset command does not exit from Unlock Bypass Mode.

## Chip Erase Command.

The Chip Erase command can be used to erase the entire chip. Six Bus Write operations are required to issue the Chip Erase Command and start the Program/Erase Controller.

If any blocks are protected then these are ignored and all the other blocks are erased. If all of the blocks are protected the Chip Erase operation appears to start but will terminate within about 100µs, leaving the data unchanged. No error condition is given when protected blocks are ignored.

During the erase operation the memory will ignore all commands, including the Erase Suspend com-



mand. It is not possible to issue any command to abort the operation. Typical chip erase times are given in Table 6. All Bus Read operations during the Chip Erase operation will output the Status Register on the Data Inputs/Outputs. See the section on the Status Register for more details.

After the Chip Erase operation has completed the memory will return to the Read Mode, unless an error has occurred. When an error occurs the memory will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read Mode.

The Chip Erase Command sets all of the bits in unprotected blocks of the memory to '1'. All previous data is lost.

#### **Block Erase Command.**

The Block Erase command can be used to erase a list of one or more blocks. Six Bus Write operations are required to select the first block in the list. Each additional block in the list can be selected by repeating the sixth Bus Write operation using the address of the additional block. The Block Erase operation starts the Program/Erase Controller about 50µs after the last Bus Write operation. Once the Program/Erase Controller starts it is not possible to select any more blocks. Each additional block must therefore be selected within 50µs of the last block. The 50µs timer restarts when an additional block is selected. The Status Register can be read after the sixth Bus Write operation. See the Status Register section for details on how to identify if the Program/Erase Controller has started the Block Erase operation.

If any selected blocks are protected then these are ignored and all the other selected blocks are erased. If all of the selected blocks are protected the Block Erase operation appears to start but will terminate within about 100µs, leaving the data unchanged. No error condition is given when protected blocks are ignored.

During the Block Erase operation the memory will ignore all commands except the Erase Suspend command. Typical block erase times are given in Table 6. All Bus Read operations during the Block Erase operation will output the Status Register on the Data Inputs/Outputs. See the section on the Status Register for more details.

After the Block Erase operation has completed the memory will return to the Read Mode, unless an error has occurred. When an error occurs the memory will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read mode.

The Block Erase Command sets all of the bits in the unprotected selected blocks to '1'. All previous data in the selected blocks is lost.

#### **Erase Suspend Command.**

The Erase Suspend Command may be used to temporarily suspend a Block Erase operation and return the memory to Read mode. The command requires one Bus Write operation.

The Program/Erase Controller will suspend within the Erase Suspend Latency time of the Erase Suspend Command being issued. Once the Program/ Erase Controller has stopped the memory will be set to Read mode and the Erase will be suspended. If the Erase Suspend command is issued during the period when the memory is waiting for an additional block (before the Program/Erase Controller starts) then the Erase is suspended immediately and will start immediately when the Erase Resume Command is issued. It is not possible to select any further blocks to erase after the Erase Resume.

During Erase Suspend it is possible to Read and Program cells in blocks that are not being erased; both Read and Program operations behave as normal on these blocks. If any attempt is made to program in a protected block or in the suspended block then the Program command is ignored and the data remains unchanged. The Status Register is not read and no error condition is given. Reading from blocks that are being erased will output the Status Register.

It is also possible to issue the Auto Select, Read CFI Query and Unlock Bypass commands during an Erase Suspend. The Read/Reset command must be issued to return the device to Read Array mode before the Resume command will be accepted.

#### **Erase Resume Command.**

The Erase Resume command must be used to restart the Program/Erase Controller after an Erase Suspend. The device must be in Read Array mode before the Resume command will be accepted. An erase can be suspended and resumed more than once.

#### **Enter Extended Block Command**

The device has an extra 64 KByte block (Extended Block) that can only be accessed using the Enter Extended Block command. Three Bus write cycles are required to issue the Extended Block command. Once the command has been issued the device enters Extended Block mode where all Bus Read or Write operations to the Boot Block addresses access the Extended Block. The Extended Block (with the same address as the Boot Blocks) cannot be erased, and can be treated as one-time programmable (OTP) memory. In Extended Block mode the Boot Blocks are not accessible

To exit from the Extended Block mode the Exit Extended Block command must be issued.

**/**/

The Extended Block can be protected, however once protected the protection cannot be undone.

#### **Exit Extended Block Command**

The Exit Extended Block command is used to exit from the Extended Block mode and return the device to Read mode. Four Bus Write operations are required to issue the command.

# **Block Protect and Chip Unprotect Commands**

Groups of blocks can be protected against accidental Program or Erase. The Protection Groups are shown in Appendix A, Table 19 and Table 20, Block Addresses. The whole chip can be unprotected to allow the data inside the blocks to be changed.

Block Protect and Chip Unprotect operations are described in Appendix D.



Table 4. Commands, 16-bit mode,  $\overline{\text{BYTE}} = V_{\text{IH}}$ 

	Length		Bus Write Operations										
Command		1st		2nd		3rd		4th		5th		6th	
		Addr	Data	Addr	Data	Addr	Data	Addr	Data	Addr	Data	Addr	Data
Read/Reset	1	Х	F0										
Read/Reset	3	555	AA	2AA	55	Х	F0						
Auto Select	3	555	AA	2AA	55	555	90						
Program	4	555	AA	2AA	55	555	A0	PA	PD				
Double Word Program	3	555	50	PA0	PD0	PA1	PD1						
Unlock Bypass	3	555	AA	2AA	55	555	20						
Unlock Bypass Program	2	Х	A0	PA	PD								
Unlock Bypass Reset	2	Х	90	Х	00								
Chip Erase	6	555	AA	2AA	55	555	80	555	AA	2AA	55	555	10
Block Erase	6+	555	AA	2AA	55	555	80	555	AA	2AA	55	ВА	30
Erase Suspend	1	Х	В0										
Erase Resume	1	Х	30										
Read CFI Query	1	55	98										
Enter Extended Block	3	555	AA	2AA	55	555	88						
Exit Extended Block	4	555	AA	2AA	55	555	90	Х	00				

Note: X Don't Care, PA Program Address, PD Program Data, BA Any address in the Block. All values in the table are in hexadecimal.

The Command Interface only uses A–1, A0-A10 and DQ0-DQ7 to verify the commands; A11-A20, DQ8-DQ14 and DQ15 are Don't Care. DQ15A–1 is A–1 when BYTE is V<sub>IL</sub> or DQ15 when BYTE is V<sub>IH</sub>.

Table 5. Commands, 8-bit mode,  $\overline{\text{BYTE}} = V_{\text{IL}}$ 

	Ч					Bus \	Write O	peratio	ns				
Command	Length	1st		2nd		3rd		4th		5th		6th	
	Ľ	Add	Data	Add	Data	Add	Data	Add	Data	Add	Data	Add	Data
Dood/Dood	1	Χ	F0										
Read/Reset	3	AAA	AA	555	55	Χ	F0						
Auto Select	3	AAA	AA	555	55	AAA	90						
Program	4	AAA	AA	555	55	AAA	A0	PA	PD				
Quadruple Byte Program	5	AAA	55	PA0	PD0	PA1	PD1	PA2	PD2	PA3	PD3		
Unlock Bypass	3	AAA	AA	555	55	AAA	20						
Unlock Bypass Program	2	Χ	A0	PA	PD								
Unlock Bypass Reset	2	Χ	90	Х	00								
Chip Erase	6	AAA	AA	555	55	AAA	80	AAA	AA	555	55	AAA	10
Block Erase	6+	AAA	AA	555	55	AAA	80	AAA	AA	555	55	ВА	30
Erase Suspend	1	Χ	В0										
Erase Resume	1	Χ	30										
Read CFI Query	1	AA	98										
Enter Extended Block	3	AAA	AA	555	55	AAA	88						
Exit Extended Block	4	AAA	AA	555	55	AAA	90	Х	00				

Note: X Don't Care, PA Program Address, PD Program Data, BA Any address in the Block. All values in the table are in hexadecimal.

The Command Interface only uses A–1, A0-A10 and DQ0-DQ7 to verify the commands; A11-A20, DQ8-DQ14 and DQ15 are Don't Care. DQ15A–1 is A–1 when BYTE is V<sub>IL</sub> or DQ15 when BYTE is V<sub>IH</sub>.

Table 6. Program, Erase Times and Program, Erase Endurance Cycles

Parameter	Min	Typ <sup>(1, 2)</sup>	Max <sup>(2)</sup>	Unit
Chip Erase		80	400 <sup>(3)</sup>	s
Block Erase (64 KBytes)		0.8	6 <sup>(4)</sup>	S
Erase Suspend Latency Time			50 <sup>(4)</sup>	μs
Program (Byte or Word)		10	200 <sup>(3)</sup>	μs
Double Word Program (Byte or Word)		10	200 <sup>(3)</sup>	μs
Chip Program (Byte by Byte)		80	400 <sup>(3)</sup>	S
Chip Program (Word by Word)		40	200 <sup>(3)</sup>	S
Chip Program (Quadruple Byte or Double Word)		20	100 <sup>(3)</sup>	S
Program/Erase Cycles (per Block)	100,000			cycles
Data Retention	20			years

Note: 1. Typical values measured at room temperature and nominal voltages.

- 2. Sampled, but not 100% tested.
- 3. Maximum value measured at worst case conditions for both temperature and V<sub>CC</sub> after 100,00 program/erase cycles.
- 4. Maximum value measured at worst case conditions for both temperature and  $V_{\text{CC}}$ .



#### STATUS REGISTER

Bus Read operations from any address always read the Status Register during Program and Erase operations. It is also read during Erase Suspend when an address within a block being erased is accessed.

The bits in the Status Register are summarized in Table 7, Status Register Bits.

Data Polling Bit (DQ7). The Data Polling Bit can be used to identify whether the Program/Erase Controller has successfully completed its operation or if it has responded to an Erase Suspend. The Data Polling Bit is output on DQ7 when the Status Register is read.

During Program operations the Data Polling Bit outputs the complement of the bit being programmed to DQ7. After successful completion of the Program operation the memory returns to Read mode and Bus Read operations from the address just programmed output DQ7, not its complement.

During Erase operations the Data Polling Bit outputs '0', the complement of the erased state of DQ7. After successful completion of the Erase operation the memory returns to Read Mode.

In Erase Suspend mode the Data Polling Bit will output a '1' during a Bus Read operation within a block being erased. The Data Polling Bit will change from a '0' to a '1' when the Program/Erase Controller has suspended the Erase operation.

Figure 5, Data Polling Flowchart, gives an example of how to use the Data Polling Bit. A Valid Address is the address being programmed or an address within the block being erased.

**Toggle Bit (DQ6).** The Toggle Bit can be used to identify whether the Program/Erase Controller has successfully completed its operation or if it has responded to an Erase Suspend. The Toggle Bit is output on DQ6 when the Status Register is read.

During Program and Erase operations the Toggle Bit changes from '0' to '1' to '0', etc., with successive Bus Read operations at any address. After successful completion of the operation the memory returns to Read mode.

During Erase Suspend mode the Toggle Bit will output when addressing a cell within a block being erased. The Toggle Bit will stop toggling when the Program/Erase Controller has suspended the Erase operation.

Figure 6, Data Toggle Flowchart, gives an example of how to use the Data Toggle Bit.

Error Bit (DQ5). The Error Bit can be used to identify errors detected by the Program/Erase Controller. The Error Bit is set to '1' when a Program, Block Erase or Chip Erase operation fails to write the correct data to the memory. If the Error Bit is set a Read/Reset command must be issued before other commands are issued. The Error bit is output on DQ5 when the Status Register is read.

Note that the Program command cannot change a bit set to '0' back to '1' and attempting to do so will set DQ5 to '1'. A Bus Read operation to that address will show the bit is still '0'. One of the Erase commands must be used to set all the bits in a block or in the whole memory from '0' to '1'.

Erase Timer Bit (DQ3). The Erase Timer Bit can be used to identify the start of Program/Erase Controller operation during a Block Erase command. Once the Program/Erase Controller starts erasing the Erase Timer Bit is set to '1'. Before the Program/Erase Controller starts the Erase Timer Bit is set to '0' and additional blocks to be erased may be written to the Command Interface. The Erase Timer Bit is output on DQ3 when the Status Register is read.

Alternative Toggle Bit (DQ2). The Alternative Toggle Bit can be used to monitor the Program/ Erase controller during Erase operations. The Alternative Toggle Bit is output on DQ2 when the Status Register is read.

During Chip Erase and Block Erase operations the Toggle Bit changes from '0' to '1' to '0', etc., with successive Bus Read operations from addresses within the blocks being erased. A protected block is treated the same as a block not being erased. Once the operation completes the memory returns to Read mode.

During Erase Suspend the Alternative Toggle Bit changes from '0' to '1' to '0', etc. with successive Bus Read operations from addresses within the blocks being erased. Bus Read operations to addresses within blocks not being erased will output the memory cell data as if in Read mode.

After an Erase operation that causes the Error Bit to be set the Alternative Toggle Bit can be used to identify which block or blocks have caused the error. The Alternative Toggle Bit changes from '0' to '1' to '0', etc. with successive Bus Read Operations from addresses within blocks that have not erased correctly. The Alternative Toggle Bit does not change if the addressed block has erased correctly.

Table 7. Status Register Bits

Operation	Address	DQ7	DQ6	DQ5	DQ3	DQ2	RB
Program	Any Address	DQ7	Toggle	0	_	_	0

**57** 

Operation	Address	DQ7	DQ6	DQ5	DQ3	DQ2	RB
Program During Erase Suspend	Any Address	DQ7	Toggle	0	-	-	0
Program Error	Any Address	DQ7	Toggle	1	_	_	0
Chip Erase	Any Address	0	Toggle	0	1	Toggle	0
Block Erase before	Erasing Block	0	Toggle	0	0	Toggle	0
timeout	Non-Erasing Block	0	Toggle	0	0	No Toggle	0
Block Erase	Erasing Block	0	Toggle	0	1	Toggle	0
DIOCK LIASE	Non-Erasing Block	0	Toggle	0	1	No Toggle	0
Erase Suspend	Erasing Block	1	No Toggle	0	_	Toggle	Hi-Z
Erase Suspend	Non-Erasing Block		Data	read as no	rmal		Hi-Z
Erase Error	Good Block Address	0	Toggle	1	1	No Toggle	0
LIASE LIIUI	Faulty Block Address	0	Toggle	1	1	Toggle	0

Note: Unspecified data bits should be ignored.

Figure 5. Data Polling Flowchart

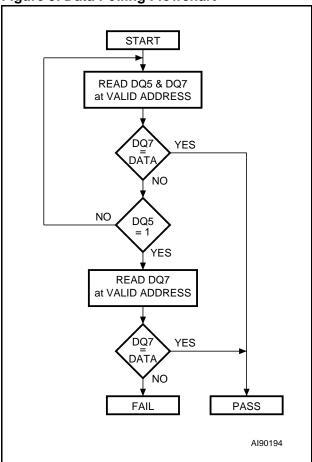
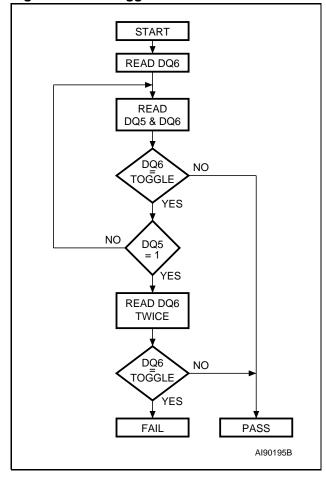


Figure 6. Data Toggle Flowchart



#### **MAXIMUM RATING**

Stressing the device above the rating listed in the Absolute Maximum Ratings table may cause permanent damage to the device. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability. These are stress ratings only and operation of the device at

these or any other conditions above those indicated in the Operating sections of this specification is not implied. Refer also to the STMicroelectronics SURE Program and other relevant quality documents.

**Table 8. Absolute Maximum Ratings** 

Symbol	Parameter	Min	Max	Unit
T <sub>BIAS</sub>	Temperature Under Bias	<b>-</b> 50	125	°C
T <sub>STG</sub>	Storage Temperature	-65	150	°C
T <sub>LEAD</sub>	Lead Temperature during Soldering <sup>(1)</sup>		260 <sup>(2)</sup>	°C
V <sub>IO</sub>	Input or Output Voltage (3,4)	-0.6	V <sub>CC</sub> +0.6	V
Vcc	Supply Voltage	-0.6	4	V
V <sub>ID</sub>	Identification Voltage	-0.6	13.5	V
V <sub>PP</sub> <sup>(5)</sup>	Program Voltage	-0.6	13.5	V

Note: 1. Compliant with the ECOPACK® 7191395 specification for Lead-free soldering processes.

- 2. Not exceeding 250°C for more than 30s, and peaking at 260°C.
- 3. Minimum voltage may undershoot to -2V during transition and for less than 20ns during transitions.
- 4. Maximum voltage may overshoot to V<sub>CC</sub> +2V during transition and for less than 20ns during transitions.
- 5. V<sub>PP</sub> must not remain at 12V for more than a total of 80hrs.

#### DC AND AC PARAMETERS

This section summarizes the operating and measurement conditions, and the DC and AC characteristics of the device. The parameters in the DC and AC Characteristic tables that follow are derived from tests performed under the Measure-

ment Conditions summarized in the relevant tables. Designers should check that the operating conditions in their circuit match the measurement conditions when relying on the quoted parameters.

**Table 9. Operating and AC Measurement Conditions** 

Parameter	M29W64	Unit	
Farameter	Min	Max	Onit
V <sub>CC</sub> Supply Voltage	2.7	3.6	V
Ambient Operating Temperature	-40	85	°C
Load Capacitance (C <sub>L</sub> )	30	30	
Input Rise and Fall Times	10		ns
Input Pulse Voltages	0 to V <sub>CC</sub>		V
Input and Output Timing Ref. Voltages	V <sub>CC</sub> /2	V	

Figure 7. AC Measurement I/O Waveform

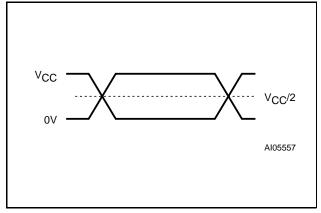


Figure 8. AC Measurement Load Circuit

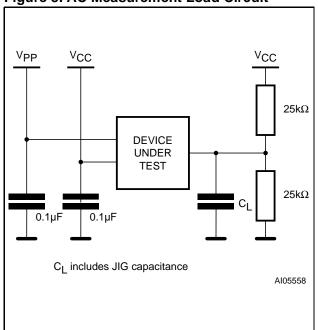


Table 10. Device Capacitance

Symbol	Symbol Parameter Test Condition Min		Max	Unit	
C <sub>IN</sub>	Input Capacitance	$V_{IN} = 0V$		6	pF
Соит	Output Capacitance	V <sub>OUT</sub> = 0V		12	pF

Note: Sampled only, not 100% tested.

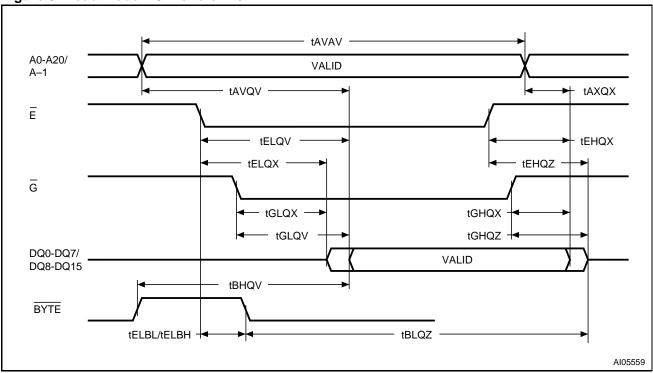


**Table 11. DC Characteristics** 

Symbol	Parameter	Test Co	ndition	Min	Max	Unit
ILI	Input Leakage Current	0V ≤ V <sub>IN</sub>	ı ≤ V <sub>CC</sub>		±1	μΑ
I <sub>LO</sub>	Output Leakage Current	0V ≤ V <sub>OU</sub>	<sub>IT</sub> ≤ V <sub>CC</sub>		±1	μΑ
I <sub>CC1</sub>	Supply Current (Read)	$\overline{E} = V_{IL}, \overline{C}$ f = 6N	,		10	mA
I <sub>CC2</sub>	Supply Current (Standby)	E = V <sub>CC</sub> RP = V <sub>C</sub>			100	μΑ
I <sub>CC3</sub>	Supply Current (Program/ Erase)	Program/Erase Controller active			20	mA
	Liasej	$V_{PP}/\overline{WP} = V_{PP}$			20	mA
V <sub>IL</sub>	Input Low Voltage			-0.5	0.8	V
V <sub>IH</sub>	Input High Voltage			0.7V <sub>CC</sub>	V <sub>CC</sub> +0.3	V
V <sub>PP</sub>	Voltage for V <sub>PP</sub> /WP Program Acceleration	V <sub>CC</sub> = 2.7	'V ±10%	11.5	12.5	V
Ірр	Current for V <sub>PP</sub> /WP Program Acceleration	V <sub>CC</sub> = 2.7	'V ±10%		15	mA
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 1	I <sub>OL</sub> = 1.8mA		0.45	V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -100μA		V <sub>CC</sub> -0.4		V
V <sub>ID</sub>	Identification Voltage			11.5	12.5	V
V <sub>LKO</sub> (1)	Program/Erase Lockout Supply Voltage			1.8	2.3	V

Note: 1. Sampled only, not 100% tested.

Figure 9. Read Mode AC Waveforms



**Table 12. Read AC Characteristics** 

Symbol	Alt	Parameter	Test Cond	dition	M29W640D	Unit
t <sub>AVAV</sub>	t <sub>RC</sub>	Address Valid to Next Address Valid	$\overline{E} = V_{IL},$ $\overline{G} = V_{IL}$	Min	90	ns
t <sub>AVQV</sub>	t <sub>ACC</sub>	Address Valid to Output Valid	$\overline{E} = V_{IL},$ $\overline{G} = V_{IL}$	Max	90	ns
t <sub>ELQX</sub> (1)	$t_{LZ}$	Chip Enable Low to Output Transition	$\overline{G} = V_{IL}$	Min	0	ns
t <sub>ELQV</sub>	t <sub>CE</sub>	Chip Enable Low to Output Valid	$\overline{G} = V_{IL}$	Max	90	ns
t <sub>GLQX</sub> (1)	toLZ	Output Enable Low to Output Transition	Output Enable Low to Output Transition $\overline{E} = V_{IL}$		0	ns
t <sub>GLQV</sub>	toE	Output Enable Low to Output Valid	Output Enable Low to Output Valid $\overline{E} = V_{IL}$		35	ns
t <sub>EHQZ</sub> (1)	t <sub>HZ</sub>	Chip Enable High to Output Hi-Z	$\overline{G} = V_{IL}$	Max	30	ns
t <sub>GHQZ</sub> (1)	t <sub>DF</sub>	Output Enable High to Output Hi-Z	$\overline{E} = V_{IL}$	Max	30	ns
t <sub>EHQX</sub> t <sub>GHQX</sub> t <sub>AXQX</sub>	tон	Chip Enable, Output Enable or Address Transition to Output Transition		Min	0	ns
t <sub>ELBL</sub> t <sub>ELBH</sub>	t <sub>ELFL</sub> t <sub>ELFH</sub>	hip Enable to BYTE Low or High		Max	5	ns
t <sub>BLQZ</sub>	t <sub>FLQZ</sub>	BYTE Low to Output Hi-Z		Max	30	ns
t <sub>BHQV</sub>	t <sub>FHQV</sub>	BYTE High to Output Valid		Max	40	ns

Note: 1. Sampled only, not 100% tested.



tAVAV -A0-A20/ VALID A-1 tWLAX tAVWL tWHEH -Ē tELWL tWHGL G tGHWL tWLWH ·  $\overline{\mathsf{w}}$ tWHWL tDVWH tWHDX DQ0-DQ7/ VALID DQ8-DQ15 VCC tVCHEL - ${\sf RB}^$ tWHRL + AI05560

Figure 10. Write AC Waveforms, Write Enable Controlled

Table 13. Write AC Characteristics, Write Enable Controlled

Symbol	Alt	Parameter		M29W640D	Unit
t <sub>AVAV</sub>	twc	Address Valid to Next Address Valid	Min	90	ns
t <sub>ELWL</sub>	t <sub>CS</sub>	Chip Enable Low to Write Enable Low	Min	0	ns
t <sub>WLWH</sub>	t <sub>WP</sub>	Write Enable Low to Write Enable High	Min	50	ns
tD∨WH	t <sub>DS</sub>	Input Valid to Write Enable High	Min	50	ns
t <sub>WHDX</sub>	t <sub>DH</sub>	Write Enable High to Input Transition	Write Enable High to Input Transition Min		ns
twheh	tcH	Write Enable High to Chip Enable High	Vrite Enable High to Chip Enable High Min		ns
t <sub>WHWL</sub>	t <sub>WPH</sub>	Write Enable High to Write Enable Low	Min	30	ns
t <sub>AVWL</sub>	t <sub>AS</sub>	Address Valid to Write Enable Low	Min	0	ns
t <sub>WLAX</sub>	t <sub>AH</sub>	Write Enable Low to Address Transition	Min	50	ns
tGHWL		Output Enable High to Write Enable Low	Min	0	ns
twHGL	t <sub>OEH</sub>	Write Enable High to Output Enable Low	Vrite Enable High to Output Enable Low Min		ns
t <sub>WHRL</sub> (1)	tBUSY	Program/Erase Valid to RB Low Max		35	ns
tvchel	t <sub>VCS</sub>	V <sub>CC</sub> High to Chip Enable Low Min		50	μs

Note: 1. Sampled only, not 100% tested.

tAVAV A0-A20/ VALID A-1 tELAX tAVEL: - tEHWH  $\overline{\mathsf{W}}$ tWLEL tEHGL G tGHEL tELEH : Ē tEHEL tDVEH tEHDX DQ0-DQ7/ VALID DQ8-DQ15 Vcc tVCHWL-RB tEHRL 🕂 AI05561

Figure 11. Write AC Waveforms, Chip Enable Controlled

Table 14. Write AC Characteristics, Chip Enable Controlled

Symbol	Alt	Parameter		M29W640D	Unit
t <sub>AVAV</sub>	t <sub>WC</sub>	Address Valid to Next Address Valid	Min	90	ns
t <sub>WLEL</sub>	t <sub>WS</sub>	Write Enable Low to Chip Enable Low	Min	0	ns
tELEH	t <sub>CP</sub>	Chip Enable Low to Chip Enable High	Min	50	ns
t <sub>DVEH</sub>	t <sub>DS</sub>	Input Valid to Chip Enable High	Min	50	ns
t <sub>EHDX</sub>	t <sub>DH</sub>	Chip Enable High to Input Transition Min		0	ns
t <sub>EHWH</sub>	t <sub>WH</sub>	Chip Enable High to Write Enable High Min		0	ns
t <sub>EHEL</sub>	tcph	Chip Enable High to Chip Enable Low	Chip Enable High to Chip Enable Low Min		ns
taveL	t <sub>AS</sub>	Address Valid to Chip Enable Low	Min	0	ns
t <sub>ELAX</sub>	t <sub>AH</sub>	Chip Enable Low to Address Transition	Min	50	ns
tGHEL		Output Enable High Chip Enable Low	Min	0	ns
t <sub>EHGL</sub>	toeh	Chip Enable High to Output Enable Low	Chip Enable High to Output Enable Low Min		ns
t <sub>EHRL</sub> (1)	t <sub>BUSY</sub>	Program/Erase Valid to RB Low	Max	35	ns
t <sub>VCHWL</sub>	t <sub>VCS</sub>	V <sub>CC</sub> High to Write Enable Low	Min	50	μs

Note: 1. Sampled only, not 100% tested.



Figure 12. Reset/Block Temporary Unprotect AC Waveforms

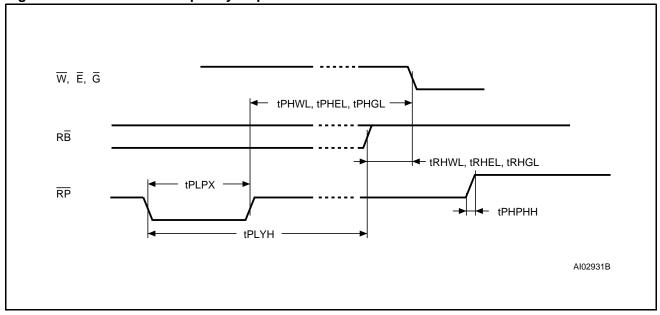
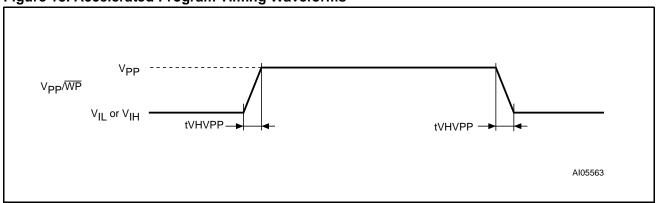


Table 15. Reset/Block Temporary Unprotect AC Characteristics

Symbol	Alt	Parameter		M29W640D	Unit
t <sub>PHWL</sub> <sup>(1)</sup> t <sub>PHEL</sub> t <sub>PHGL</sub> <sup>(1)</sup>	t <sub>RH</sub>	RP High to Write Enable Low, Chip Enable Low, Output Enable Low		50	ns
t <sub>RHWL</sub> <sup>(1)</sup> t <sub>RHEL</sub> <sup>(1)</sup> t <sub>RHGL</sub> <sup>(1)</sup>	t <sub>RB</sub>	RB High to Write Enable Low, Chip Enable Low, Output Enable Low		0	ns
t <sub>PLPX</sub>	t <sub>RP</sub>	RP Pulse Width	Min	500	ns
tplyh	t <sub>READY</sub>	RP Low to Read Mode	Max	50	μs
t <sub>PHPHH</sub> (1)	$t_{VIDR}$	RP Rise Time to V <sub>ID</sub>		500	ns
t <sub>VHVPP</sub> (1)		V <sub>PP</sub> Rise and Fall Time	Min	250	ns

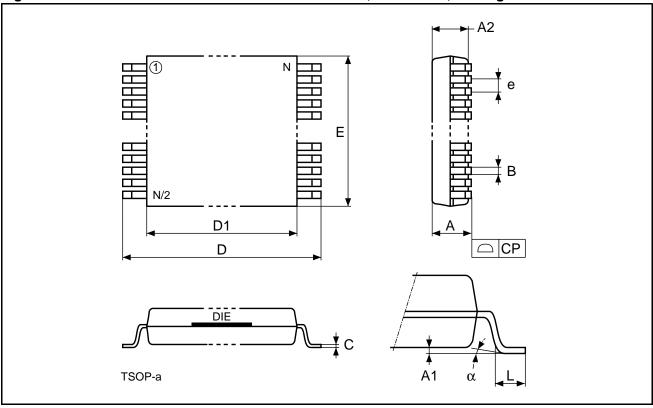
Note: 1. Sampled only, not 100% tested.

Figure 13. Accelerated Program Timing Waveforms



# **PACKAGE MECHANICAL**

Figure 14. TSOP48 – 48 lead Plastic Thin Small Outline, 12 x 20mm, Package Outline



Note: Drawing is not to scale.

Table 16. TSOP48 – 48 lead Plastic Thin Small Outline, 12 x 20mm, Package Mechanical Data

Cumbal		millimeters	eters		inches	
Symbol	Тур	Min	Max	Тур	Min	Max
А			1.200			0.0472
A1	0.100	0.050	0.150	0.0039	0.0020	0.0059
A2	1.000	0.950	1.050	0.0394	0.0374	0.0413
В		0.170	0.270		0.0067	0.0106
С		0.100	0.210		0.0039	0.0083
СР			0.100			0.0039
D		19.800	20.200		0.7795	0.7953
D1		18.300	18.500		0.7205	0.7283
е	0.500	-	-	0.0197	-	_
E		11.900	12.100		0.4685	0.4764
L		0.500	0.700		0.0197	0.0276
alfa		0	5		0	5
N	48			48		

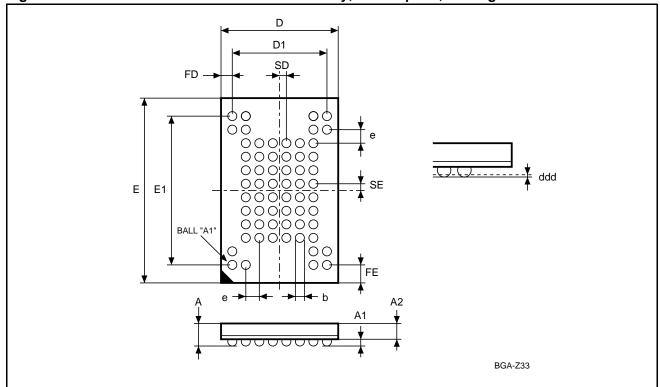


Figure 15. TFBGA63 7x11mm - 6x8 active ball array, 0.8mm pitch, Package Outline

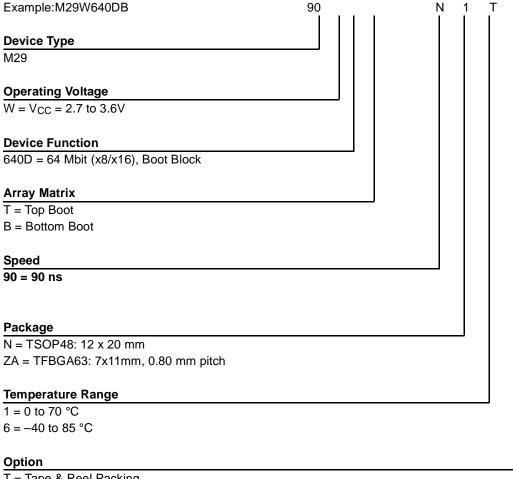
Note: Drawing is not to scale.

Table 17. TFBGA63 7x11mm - 6x8 active ball array, 0.8mm pitch, Package Mechanical Data

Symbol		millimeters			inches		
Syllibol	Тур	Min	Max	Тур	Min	Max	
А			1.200			0.0472	
A1		0.250			0.0098		
A2			0.900			0.0354	
b		0.350	0.450		0.0138	0.0177	
D	7.000	6.900	7.100	0.2756	0.2717	0.2795	
D1	5.600	_	_	0.2205	-	_	
ddd	-	_	0.100	-	-	0.0039	
E	11.000	10.900	11.100	0.4331	0.4291	0.4370	
E1	8.800	_	-	0.3465	-	_	
е	0.800	_	-	0.0315	-	_	
FD	0.700	-	-	0.0276	_	_	
FE	1.100	-	-	0.0433	-	-	
SD	0.400	-	-	0.0157	-	-	
SE	0.400	-	_	0.0157	_	-	

#### **PART NUMBERING**

# **Table 18. Ordering Information Scheme**



T = Tape & Reel Packing

E = Lead-free Package, Standard Packing

F = Lead-free Package, Tape & Reel Packing

Note: This product is also available with the Extended Block factory locked. For further details and ordering information contact your nearest ST sales office.

Devices are shipped from the factory with the memory content bits erased to 1. For a list of available options (Speed, Package, etc.) or for further information on any aspect of this device, please contact your nearest ST Sales Office.



# **APPENDIX A. BLOCK ADDRESSES**

Table 19. Top Boot Block Addresses, M29W640DT

Block	KBytes/ KWords	Protection Block Group	(x8)	(x16)
0	64/32		000000h-00FFFFh	000000h-007FFFh
1	64/32	Drotoction Croup	010000h-01FFFFh	008000h-00FFFFh
2	64/32	Protection Group	020000h-02FFFFh	010000h-017FFFh
3	64/32	<u> </u>	030000h-03FFFFh	018000h-01FFFFh
4	64/32		040000h-04FFFFh	020000h-027FFFh
5	64/32	Protection Croup	050000h-05FFFFh	028000h-02FFFFh
6	64/32	Protection Group	060000h-06FFFFh	030000h-037FFFh
7	64/32	]	070000h-07FFFFh	038000h-03FFFFh
8	64/32		080000h-08FFFFh	040000h-047FFFh
9	64/32	Protection Croup	090000h-09FFFFh	048000h-04FFFFh
10	64/32	Protection Group	0A0000h-0AFFFFh	050000h-057FFFh
11	64/32	]	0B0000h-0BFFFFh	058000h-05FFFFh
12	64/32		0C0000h-0CFFFFh	060000h-067FFFh
13	64/32	Protection Group	0D0000h-0DFFFFh	068000h-06FFFFh
14	64/32	- Protection Group	0E0000h-0EFFFFh	070000h-077FFFh
15	64/32	]	0F0000h-0FFFFh	078000h-07FFFFh
16	64/32		100000h-10FFFFh	080000h-087FFFh
17	64/32	Protection Group	110000h-11FFFFh	088000h-08FFFFh
18	64/32	- Protection Group	120000h-12FFFFh	090000h-097FFFh
19	64/32	]	130000h-13FFFFh	098000h-09FFFFh
20	64/32		140000h-14FFFFh	0A0000h-0A7FFFh
21	64/32	Protection Group	150000h-15FFFFh	0A8000h-0AFFFFh
22	64/32	Frotection Group	160000h-16FFFFh	0B0000h-0B7FFFh
23	64/32		170000h-17FFFFh	0B8000h-0BFFFFh
24	64/32		180000h-18FFFFh	0C0000h-0C7FFFh
25	64/32	Protection Group	190000h-19FFFFh	0C8000h-0CFFFFh
26	64/32	1 Totection Group	1A0000h-1AFFFFh	0D0000h-0D7FFFh
27	64/32		1B0000h-1BFFFFh	0D8000h-0DFFFFh
28	64/32		1C0000h-1CFFFFh	0E0000h-0E7FFh
29	64/32	Protection Group	1D0000h-1DFFFFh	0E8000h-0EFFFFh
30	64/32	FTOTECTION GIOUP	1E0000h-1EFFFFh	0F0000h-0F7FFh
31	64/32		1F0000h-1FFFFFh	0F8000h-0FFFFFh

Block	KBytes/ KWords	Protection Block Group	(x8)	(x16)
32	64/32		200000h-20FFFFh	100000h-107FFFh
33	64/32	Drotostian Crown	210000h-21FFFFh	108000h-10FFFFh
34	64/32	Protection Group	220000h-22FFFFh	110000h-117FFFh
35	64/32	]	230000h-23FFFFh	118000h-11FFFFh
36	64/32		240000h-24FFFFh	120000h-127FFFh
37	64/32	Protection Group	250000h-25FFFFh	128000h-12FFFFh
38	64/32	- Protection Group	260000h-26FFFFh	130000h-137FFFh
39	64/32	]	270000h-27FFFFh	138000h-13FFFFh
40	64/32		280000h-28FFFFh	140000h-147FFFh
41	64/32	Drataction Croup	290000h-29FFFFh	148000h-14FFFFh
42	64/32	Protection Group	2A0000h-2AFFFFh	150000h-157FFFh
43	64/32	<b>]</b>	2B0000h-2BFFFFh	158000h-15FFFFh
44	64/32		2C0000h-2CFFFFh	160000h-167FFFh
45	64/32	Drotostian Crown	2D0000h-2DFFFFh	168000h-16FFFFh
46	64/32	Protection Group	2E0000h-2EFFFFh	170000h-177FFFh
47	64/32	]	2F0000h-2FFFFFh	178000h-17FFFFh
48	64/32		300000h-30FFFFh	180000h-187FFFh
49	64/32	Protection Croup	310000h-31FFFFh	188000h-18FFFFh
50	64/32	Protection Group	320000h-32FFFFh	190000h-197FFFh
51	64/32		330000h-33FFFFh	198000h-19FFFFh
52	64/32		340000h-34FFFFh	1A0000h-1A7FFFh
53	64/32	Protection Croup	350000h-35FFFFh	1A8000h-1AFFFFh
54	64/32	Protection Group	360000h-36FFFFh	1B0000h-1B7FFFh
55	64/32	]	370000h-37FFFFh	1B8000h-1BFFFFh
56	64/32		380000h-38FFFFh	1C0000h-1C7FFFh
57	64/32	Drataction Croup	390000h-39FFFFh	1C8000h-1CFFFFh
58	64/32	Protection Group	3A0000h-3AFFFFh	1D0000h-1D7FFFh
59	64/32	]	3B0000h-3BFFFFh	1D8000h-1DFFFFh
60	64/32		3C0000h-3CFFFFh	1E0000h-1E7FFFh
61	64/32	Protection Group	3D0000h-3DFFFFh	1E8000h-1EFFFFh
62	64/32	FTOTECTION GLOUP	3E0000h-3EFFFFh	1F0000h-1F7FFFh
63	64/32	<u>]</u>	3F0000h-3FFFFFh	1F8000h-1FFFFFh



Block	KBytes/ KWords	Protection Block Group	(x8)	(x16)
64	64/32		400000h-40FFFFh	200000h-207FFFh
65	64/32	Drata etia in Cravin	410000h-41FFFFh	208000h-20FFFFh
66	64/32	Protection Group	420000h-42FFFFh	210000h-217FFFh
67	64/32		430000h-43FFFFh	218000h-21FFFFh
68	64/32		440000h-44FFFFh	220000h-227FFFh
69	64/32	Protection Group	450000h-45FFFFh	228000h-22FFFFh
70	64/32	Protection Group	460000h-46FFFFh	230000h-237FFFh
71	64/32		470000h-47FFFFh	238000h-23FFFFh
72	64/32		480000h-48FFFFh	240000h-247FFFh
73	64/32	Protection Group	490000h-49FFFFh	248000h-24FFFFh
74	64/32	- Protection Group	4A0000h-4AFFFFh	250000h-257FFFh
75	64/32	1	4B0000h-4BFFFFh	258000h-25FFFFh
76	64/32		4C0000h-4CFFFFh	260000h-267FFh
77	64/32	Drataction Croup	4D0000h-4DFFFFh	268000h-26FFFFh
78	64/32	Protection Group	4E0000h-4EFFFFh	270000h-277FFFh
79	64/32	1	4F0000h-4FFFFFh	278000h-27FFFFh
80	64/32		500000h-50FFFFh	280000h-287FFFh
81	64/32	Protection Group	510000h-51FFFFh	288000h-28FFFFh
82	64/32	Protection Group	520000h-52FFFFh	290000h-297FFFh
83	64/32		530000h-53FFFFh	298000h-29FFFFh
84	64/32		540000h-54FFFFh	2A0000h-2A7FFFh
85	64/32	Protection Group	550000h-55FFFFh	2A8000h-2AFFFFh
86	64/32	Frotection Group	560000h-56FFFFh	2B0000h-2B7FFFh
87	64/32	1	570000h-57FFFh	2B8000h-2BFFFFh
88	64/32		580000h-58FFFFh	2C0000h-2C7FFFh
89	64/32	Protection Group	590000h-59FFFFh	2C8000h-2CFFFFh
90	64/32	Frotection Group	5A0000h-5AFFFFh	2D0000h-2D7FFFh
91	64/32		5B0000h-5BFFFFh	2D8000h-2DFFFFh
92	64/32		5C0000h-5CFFFFh	2E0000h-2E7FFFh
93	64/32	Protection Group	5D0000h-5DFFFFh	2E8000h-2EFFFFh
94	64/32		5E0000h-5EFFFFh	2F0000h-2F7FFFh
95	64/32		5F0000h-5FFFFFh	2F8000h-2FFFFFh

Block	KBytes/ KWords	Protection Block Group	(x8)	(x16)
96	64/32	Production Consum	600000h-60FFFFh	300000h-307FFFh
97	64/32		610000h-61FFFFh	308000h-30FFFFh
98	64/32	Protection Group	620000h-62FFFFh	310000h-317FFFh
99	64/32	1	630000h-63FFFFh	318000h-31FFFFh
100	64/32		640000h-64FFFFh	320000h-327FFFh
101	64/32	Drotostian Crown	650000h-65FFFFh	328000h-32FFFFh
102	64/32	Protection Group	660000h-66FFFFh	330000h-337FFFh
103	64/32	1	670000h-67FFFh	338000h-33FFFFh
104	64/32		680000h-68FFFFh	340000h-347FFFh
105	64/32	Drotostian Crown	690000h-69FFFFh	348000h-34FFFFh
106	64/32	Protection Group	6A0000h-6AFFFFh	350000h-357FFFh
107	64/32	1	6B0000h-6BFFFFh	358000h-35FFFFh
108	64/32		6C0000h-6CFFFFh	360000h-367FFFh
109	64/32	Drotostian Crown	6D0000h-6DFFFFh	368000h-36FFFFh
110	64/32	Protection Group	6E0000h-6EFFFFh	370000h-377FFFh
111	64/32	1	6F0000h-6FFFFFh	378000h-37FFFFh
112	64/32		700000h-70FFFFh	380000h-387FFFh
113	64/32	Drataction Croup	710000h-71FFFFh	388000h-38FFFFh
114	64/32	Protection Group	720000h-72FFFFh	390000h-397FFFh
115	64/32	1 1	730000h-73FFFFh	398000h-39FFFFh
116	64/32		740000h-74FFFFh	3A0000h-3A7FFFh
117	64/32	Protection Crows	750000h-75FFFFh	3A8000h-3AFFFFh
118	64/32	Protection Group	760000h-76FFFFh	3B0000h-3B7FFFh
119	64/32	1	770000h-77FFFFh	3B8000h-3BFFFFh
120	64/32		780000h-78FFFFh	3C0000h-3C7FFFh
121	64/32	Droto oti O	790000h-79FFFFh	3C8000h-3CFFFFh
122	64/32	Protection Group	7A0000h-7AFFFFh	3D0000h-3D7FFFh
123	64/32		7B0000h-7BFFFFh	3D8000h-3DFFFFh



Block	KBytes/ KWords	Protection Block Group	(x8)	(x16)
124	64/32		7C0000h-7CFFFFh	3E0000h-3E7FFFh
125	64/32		7D0000h-7DFFFFh	3E8000h-3EFFFFh
126	64/32		7E0000h-7EFFFFh	3F0000h-3F7FFFh
127	8/4		7F0000h-7F1FFFh <sup>(1)</sup>	3F8000h-3F8FFFh <sup>(1)</sup>
128	8/4		7F2000h-7F3FFFh <sup>(1)</sup>	3F9000h-3F9FFFh <sup>(1)</sup>
129	8/4	Protection Group	7F4000h-7F5FFFh <sup>(1)</sup>	3FA000h-3FAFFFh <sup>(1)</sup>
130	8/4		7F6000h-7F7FFFh <sup>(1)</sup>	3FB000h-3FBFFFh <sup>(1)</sup>
131	8/4		7F8000h-7F9FFFh <sup>(1)</sup>	3FC000h-3FCFFFh <sup>(1)</sup>
132	8/4		7FA000h–7FBFFFh <sup>(1)</sup>	3FD000h-3FDFFFh <sup>(1)</sup>
133	8/4		7FC000h-7FDFFFh <sup>(1)</sup>	3FE000h-3FEFFFh <sup>(1)</sup>
134	8/4		7FE000h-7FFFFFh <sup>(1)</sup>	3FF000h-3FFFFFh <sup>(1)</sup>

Note: 1. Used as the Extended Block Addresses in Extended Block mode.

Table 20. Bottom Boot Block Addresses, M29W640DB

Block	KBytes/ KWords	Protection Block Group	(x8)	(x16)
0	8/4		000000h-001FFFh <sup>(1)</sup>	000000h-000FFFh <sup>(1)</sup>
1	8/4		002000h-003FFFh <sup>(1)</sup>	001000h-001FFFh <sup>(1)</sup>
2	8/4		004000h-005FFFh <sup>(1)</sup>	002000h-002FFFh <sup>(1)</sup>
3	8/4	]	006000h-007FFFh <sup>(1)</sup>	003000h-003FFFh <sup>(1)</sup>
4	8/4		008000h-009FFFh <sup>(1)</sup>	004000h-004FFFh <sup>(1)</sup>
5	8/4	Protection Group	00A000h-00BFFFh <sup>(1)</sup>	005000h-005FFFh <sup>(1)</sup>
6	8/4		00C000h-00DFFFh <sup>(1)</sup>	006000h-006FFFh <sup>(1)</sup>
7	8/4		00E000h-00FFFFh <sup>(1)</sup>	007000h-007FFFh <sup>(1)</sup>
8	64/32	1	010000h-01FFFFh	008000h-00FFFFh
9	64/32	1	020000h-02FFFFh	010000h-017FFFh
10	64/32	1	030000h-03FFFFh	018000h-01FFFFh
11	64/32	Protection Group	040000h-04FFFFh	020000h-027FFFh
12	64/32		050000h-05FFFFh	028000h-02FFFFh
13	64/32		060000h-06FFFFh	030000h-037FFFh
14	64/32		070000h-07FFFFh	038000h-03FFFFh

Block	KBytes/ KWords	Protection Block Group	(x8)	(x16)
15	64/32	Protection Group	080000h-08FFFFh	040000h-047FFFh
16	64/32		090000h-09FFFFh	048000h-04FFFFh
17	64/32		0A0000h-0AFFFFh	050000h-057FFFh
18	64/32		0B0000h-0BFFFFh	058000h-05FFFFh
19	64/32		0C0000h-0CFFFFh	060000h-067FFh
20	64/32	Drataction Croup	0D0000h-0DFFFFh	068000h-06FFFFh
21	64/32	Protection Group	0E0000h-0EFFFFh	070000h-077FFFh
22	64/32	]	0F0000h-0FFFFFh	078000h-07FFFFh
23	64/32		100000h-10FFFFh	080000h-087FFFh
24	64/32	Drataction Croup	110000h-11FFFFh	088000h-08FFFFh
25	64/32	Protection Group	120000h-12FFFFh	090000h-097FFFh
26	64/32	<b>-</b>	130000h-13FFFFh	098000h-09FFFFh
27	64/32		140000h-14FFFFh	0A0000h-0A7FFFh
28	64/32	Drestantian Crown	150000h-15FFFFh	0A8000h-0AFFFFh
29	64/32	Protection Group	160000h-16FFFFh	0B0000h-0B7FFFh
30	64/32	<b>-</b>	170000h-17FFFFh	0B8000h-0BFFFFh
31	64/32		180000h-18FFFFh	0C0000h-0C7FFFh
32	64/32	Drataction Croup	190000h-19FFFFh	0C8000h-0CFFFFh
33	64/32	Protection Group	1A0000h-1AFFFFh	0D0000h-0D7FFFh
34	64/32	]	1B0000h-1BFFFFh	0D8000h-0DFFFFh
35	64/32		1C0000h-1CFFFFh	0E0000h-0E7FFh
36	64/32	Protection Croup	1D0000h-1DFFFFh	0E8000h-0EFFFFh
37	64/32	Protection Group	1E0000h-1EFFFFh	0F0000h-0F7FFFh
38	64/32		1F0000h-1FFFFFh	0F8000h-0FFFFFh
39	64/32		200000h-20FFFFh	100000h-107FFFh
40	64/32	- Protection Group	210000h-21FFFFh	108000h-10FFFFh
41	64/32		220000h-22FFFFh	110000h-117FFFh
42	64/32	]	230000h-23FFFFh	118000h-11FFFFh
43	64/32		240000h-24FFFFh	120000h-127FFFh
44	64/32	Protection Group	250000h-25FFFFh	128000h-12FFFFh
45	64/32		260000h-26FFFFh	130000h-137FFFh
46	64/32	] [	270000h-27FFFh	138000h-13FFFFh



Block	KBytes/ KWords	Protection Block Group	(x8)	(x16)
47	64/32	Protection Group	280000h-28FFFFh	140000h-147FFFh
48	64/32		290000h-29FFFFh	148000h-14FFFFh
49	64/32		2A0000h-2AFFFFh	150000h-157FFFh
50	64/32		2B0000h-2BFFFFh	158000h-15FFFFh
51	64/32		2C0000h-2CFFFFh	160000h-167FFFh
52	64/32	Protection Group	2D0000h-2DFFFFh	168000h-16FFFFh
53	64/32	- Protection Group	2E0000h-2EFFFFh	170000h-177FFFh
54	64/32	]	2F0000h-2FFFFFh	178000h-17FFFFh
55	64/32		300000h-30FFFFh	180000h-187FFFh
56	64/32	Protection Group	310000h-31FFFFh	188000h-18FFFFh
57	64/32	- Protection Group	320000h-32FFFFh	190000h-197FFFh
58	64/32	]	330000h-33FFFFh	198000h-19FFFFh
59	64/32		340000h-34FFFFh	1A0000h-1A7FFFh
60	64/32	Protection Group	350000h-35FFFFh	1A8000h-1AFFFFh
61	64/32	- Protection Group	360000h-36FFFFh	1B0000h-1B7FFFh
62	64/32		370000h-37FFFFh	1B8000h-1BFFFFh
63	64/32		380000h-38FFFFh	1C0000h-1C7FFFh
64	64/32	Draw and the second	390000h-39FFFFh	1C8000h-1CFFFFh
65	64/32	Protection Group	3A0000h-3AFFFFh	1D0000h-1D7FFFh
66	64/32	1 1	3B0000h-3BFFFFh	1D8000h-1DFFFFh
67	64/32		3C0000h-3CFFFFh	1E0000h-1E7FFFh
68	64/32	Protection Group	3D0000h-3DFFFFh	1E8000h-1EFFFFh
69	64/32	- Protection Group	3E0000h-3EFFFFh	1F0000h-1F7FFFh
70	64/32		3F0000h-3FFFFFh	1F8000h-1FFFFFh
71	64/32		400000h-40FFFFh	200000h-207FFFh
72	64/32	Protection Craus	410000h-41FFFFh	208000h-20FFFFh
73	64/32	Protection Group	420000h-42FFFFh	210000h-217FFFh
74	64/32		430000h-43FFFFh	218000h-21FFFFh
75	64/32		440000h-44FFFFh	220000h-227FFFh
76	64/32	Protection Group	450000h-45FFFFh	228000h-22FFFFh
77	64/32		460000h-46FFFFh	230000h-237FFFh
78	64/32	] [	470000h-47FFFFh	238000h-23FFFFh

Block	KBytes/ KWords	Protection Block Group	(x8)	(x16)
79	64/32		480000h-48FFFFh	240000h-247FFFh
80	64/32	Drataction Croup	490000h-49FFFFh	248000h-24FFFFh
81	64/32	Protection Group	4A0000h-4AFFFFh	250000h-257FFFh
82	64/32	]	4B0000h-4BFFFFh	258000h-25FFFFh
83	64/32		4C0000h-4CFFFFh	260000h-267FFh
84	64/32	Protection Group	4D0000h-4DFFFFh	268000h-26FFFFh
85	64/32	- Protection Group	4E0000h-4EFFFFh	270000h-277FFFh
86	64/32	]	4F0000h-4FFFFFh	278000h-27FFFFh
87	64/32		500000h-50FFFFh	280000h-287FFFh
88	64/32	Drataction Croup	510000h-51FFFFh	288000h-28FFFFh
89	64/32	Protection Group	520000h-52FFFFh	290000h-297FFh
90	64/32	]	530000h-53FFFFh	298000h-29FFFFh
91	64/32		540000h-54FFFFh	2A0000h-2A7FFFh
92	64/32	Drataction Croup	550000h-55FFFFh	2A8000h-2AFFFFh
93	64/32	Protection Group	560000h-56FFFFh	2B0000h-2B7FFFh
94	64/32	]	570000h-57FFFFh	2B8000h-2BFFFFh
95	64/32		580000h-58FFFFh	2C0000h-2C7FFFh
96	64/32	Protection Group	590000h-59FFFFh	2C8000h-2CFFFFh
97	64/32	Frotection Group	5A0000h-5AFFFFh	2D0000h-2D7FFFh
98	64/32		5B0000h-5BFFFFh	2D8000h-2DFFFFh
99	64/32		5C0000h-5CFFFFh	2E0000h-2E7FFFh
100	64/32	Protection Group	5D0000h-5DFFFFh	2E8000h-2EFFFFh
101	64/32	Frotection Group	5E0000h-5EFFFFh	2F0000h-2F7FFFh
102	64/32		5F0000h-5FFFFFh	2F8000h-2FFFFFh
103	64/32		600000h-60FFFh	300000h-307FFFh
104	64/32	Protection Croup	610000h-61FFFFh	308000h-30FFFFh
105	64/32	Protection Group	620000h-62FFFFh	310000h-317FFFh
106	64/32	]	630000h-63FFFFh	318000h-31FFFFh
107	64/32		640000h-64FFFFh	320000h-327FFFh
108	64/32	Protection Group	650000h-65FFFFh	328000h-32FFFFh
109	64/32	- Flotection Gloup	660000h-66FFFFh	330000h-337FFFh
110	64/32		670000h-67FFFh	338000h-33FFFFh



Block	KBytes/ KWords	Protection Block Group	(x8)	(x16)
111	64/32		680000h-68FFFFh	340000h-347FFFh
112	64/32	Drataction Croup	690000h-69FFFFh	348000h-34FFFFh
113	64/32	<ul> <li>Protection Group</li> </ul>	6A0000h-6AFFFFh	350000h-357FFFh
114	64/32	<b>1</b>	6B0000h-6BFFFFh	358000h-35FFFFh
115	64/32		6C0000h-6CFFFFh	360000h-367FFFh
116	64/32	Drataction Croup	6D0000h-6DFFFFh	368000h-36FFFFh
117	64/32	Protection Group	6E0000h-6EFFFFh	370000h-377FFFh
118	64/32	<b>1</b>	6F0000h-6FFFFFh	378000h-37FFFFh
119	64/32		700000h-70FFFh	380000h-387FFFh
120	64/32	Droto etion Crown	710000h-71FFFFh	388000h-38FFFFh
121	64/32	Protection Group	720000h-72FFFFh	390000h-397FFFh
122	64/32	<b>1</b>	730000h-73FFFFh	398000h-39FFFFh
123	64/32		740000h-74FFFFh	3A0000h-3A7FFFh
124	64/32	Dresta etia n Graun	750000h-75FFFFh	3A8000h-3AFFFFh
125	64/32	Protection Group	760000h-76FFFFh	3B0000h-3B7FFFh
126	64/32	<b>1</b>	770000h-77FFFFh	3B8000h-3BFFFFh
127	64/32		780000h-78FFFFh	3C0000h-3C7FFFh
128	64/32	Dresta etia n Graun	790000h-79FFFFh	3C8000h-3CFFFFh
129	64/32	Protection Group	7A0000h-7AFFFFh	3D0000h-3D7FFFh
130	64/32	<b>1</b>	7B0000h-7BFFFFh	3D8000h-3DFFFFh
131	64/32		7C0000h-7CFFFFh	3E0000h-3E7FFFh
132	64/32	Drotostica Crows	7D0000h-7DFFFFh	3E8000h-3EFFFFh
133	64/32	Protection Group	7E0000h-7EFFFFh	3F0000h-3F7FFFh
134	64/32	7	7F0000h-7FFFFFh	3F8000h-3FFFFFh

Note: 1. Used as the Extended Block Addresses in Extended Block mode.

## APPENDIX B. COMMON FLASH INTERFACE (CFI)

The Common Flash Interface is a JEDEC approved, standardized data structure that can be read from the Flash memory device. It allows a system software to query the device to determine various electrical and timing parameters, density information and functions supported by the memory. The system can interface easily with the device, enabling the software to upgrade itself when necessary.

When the CFI Query Command is issued the device enters CFI Query mode and the data structure is read from the memory. Table 21 to Table 26 show the addresses used to retrieve the data.

The CFI data structure also contains a security area where a 64 bit unique security number is written (see Table 26, Security Code Area). This area can be accessed only in Read mode by the final user. It is impossible to change the security number after it has been written by ST.

**Table 21. Query Structure Overview** 

Add	ress	Sub-section Name	Description	
x16	х8	Sub-section Name		
10h	20h	CFI Query Identification String	Command set ID and algorithm data offset	
1Bh	36h	System Interface Information	Device timing & voltage information	
27h	4Eh	Device Geometry Definition	Flash device layout	
40h	80h	Primary Algorithm-specific Extended Query table	Additional information specific to the Primary Algorithm (optional)	
61h	C2h	Security Code Area	64 bit unique device number	

Note: Query data are always presented on the lowest order data outputs.

Table 22. CFI Query Identification String

Add	Address		Description	Value
x16	<b>x8</b>	Data	Description	value
10h	20h	0051h		"Q"
11h	22h	0052h	Query Unique ASCII String "QRY"	"R"
12h	24h	0059h		"Y"
13h	26h	0002h	Primary Algorithm Command Set and Control Interface ID code 16 bit	
14h	28h	0000h	ID code defining a specific algorithm	Compatible
15h	2Ah	0040h	Address for Primary Algorithm extended Query table (see Table 25)	
16h	2Ch	0000h		
17h	2Eh	0000h	Alternate Vendor Command Set and Control Interface ID Code second	NA
18h	30h	0000h	vendor - specified algorithm supported	INA
19h	32h	0000h	Address for Alternate Algorithm extended Query table	NA
1Ah	34h	0000h		INA

Note: Query data are always presented on the lowest order data outputs (DQ7-DQ0) only. DQ8-DQ15 are '0'.



Table 23. CFI Query System Interface Information

Address		Data	Description	Value	
x16	x8	Data	Description	Value	
1Bh	36h	0027h	V <sub>CC</sub> Logic Supply Minimum Program/Erase voltage bit 7 to 4BCD value in volts bit 3 to 0BCD value in 100 mV	2.7V	
1Ch	38h	0036h	V <sub>CC</sub> Logic Supply Maximum Program/Erase voltage bit 7 to 4BCD value in volts bit 3 to 0BCD value in 100 mV	3.6V	
1Dh	3Ah	00B5h	V <sub>PP</sub> [Programming] Supply Minimum Program/Erase voltage bit 7 to 4HEX value in volts bit 3 to 0BCD value in 100 mV	11.5V	
1Eh	3Ch	00C5h	V <sub>PP</sub> [Programming] Supply Maximum Program/Erase voltage bit 7 to 4HEX value in volts bit 3 to 0BCD value in 100 mV	12.5V	
1Fh	3Eh	0004h	Typical timeout per single byte/word program = 2 <sup>n</sup> μs	16µs	
20h	40h	0000h	Typical timeout for minimum size write buffer program = 2 <sup>n</sup> μs	NA	
21h	42h	000Ah	Typical timeout per individual Block Erase = 2 <sup>n</sup> ms	1s	
22h	44h	0000h	Typical timeout for full Chip Erase = 2 <sup>n</sup> ms	NA	
23h	46h	0004h	Maximum timeout for byte/word program = 2 <sup>n</sup> times typical	256 µs	
24h	48h	0000h	Maximum timeout for write buffer program = 2 <sup>n</sup> times typical	NA	
25h	4Ah	0003h	Maximum timeout per individual Block Erase = 2 <sup>n</sup> times typical 8s		
26h	4Ch	0000h	Maximum timeout for Chip Erase = 2 <sup>n</sup> times typical	NA	

**Table 24. Device Geometry Definition** 

Add	Address		Description	Value
x16	x8	Data	Description	value
27h	4Eh	0017h	Device Size = 2 <sup>n</sup> in number of bytes	8 MByte
28h 29h	50h 52h	0002h 0000h	Flash Device Interface Code description	x8, x16 Async.
2Ah 2Bh	54h 56h	0000h 0000h	Maximum number of bytes in multi-byte program or page = 2 <sup>n</sup>	NA
2Ch	58h	0002h	Number of Erase Block Regions. It specifies the number of regions containing contiguous Erase Blocks of the same size.	2
2Dh 2Eh	5Ah 5Ch	0007h 0000h	Region 1 Information Number of Erase Blocks of identical size = 0007h+1	8
2Fh 30h	5Eh 60h	0020h 0000h	Region 1 Information Block size in Region 1 = 0020h * 256 byte	8Kbyte
31h 32h	62h 64h	007Eh 0000h	Region 2 Information Number of Erase Blocks of identical size= 007Eh+1	127
33h 34h	66h 68h	0000h 0001h	Region 2 Information Block size in Region 2 = 0100h * 256 byte	64Kbyte
35h 36h	6Ah 6Ch	0000h 0000h	Region 3 Information Number of Erase Blocks of identical size=007Fh+1	0
37h 38h	6Eh 70h	0000h 0000h	Region 3 Information Block size in Region 3 = 0000h * 256 byte	0
39h 3Ah	72h 74h	0000h 0000h	Region 4 Information Number of Erase Blocks of Identical size=007Fh+1	0
3Bh 3Ch	76h 78h	0000h 0000h	Region 4 Information Block size in Region 4 = 0000h * 256 byte	0

Note: For Bottom Boot devices, Erase Block Region 1 is located from address 000000h to 007FFFh and Erase Block Region 2 from address 008000h to 3FFFFFh.

For Top Boot devices, Erase Block Region 1 is located from address 000000h to 3F7FFFh and Erase Block Region 2 from address 3F8000h to 3FFFFFh.



Table 25. Primary Algorithm-Specific Extended Query Table

Add	lress	Dete	Pagarinata n	Value
x16	x8	- Data	Description	Value
40h	80h	0050h		"P"
41h	82h	0052h	Primary Algorithm extended Query table unique ASCII string "PRI"	"R"
42h	84h	0049h		" "
43h	86h	0031h	Major version number, ASCII	"1"
44h	88h	0033h	Minor version number, ASCII	"3"
45h	8Ah	0000h	Address Sensitive Unlock (bits 1 to 0) 00h = required, 01h = not required Silicon Revision Number (bits 7 to 2)	Yes
46h	8Ch	0002h	Erase Suspend 00h = not supported, 01h = Read only, 02 = Read and Write	2
47h	8Eh	0004h	Block Protection 00h = not supported, x = number of blocks per protection group	4
48h	90h	0001h	Temporary Block Unprotect 00h = not supported, 01h = supported	Yes
49h	92h	0004h	Block Protect /Unprotect 04 = M29W640D	04
4Ah	94h	0000h	Simultaneous Operations, 00h = not supported	No
4Bh	96h	0000h	Burst Mode, 00h = not supported, 01h = supported	No
4Ch	98h	0000h	Page Mode, 00h = not supported, 01h = 4 page word, 02h = 8 page word	No
4Dh	9Ah	00B5h	V <sub>PP</sub> Supply Minimum Program/Erase voltage bit 7 to 4 HEX value in volts bit 3 to 0 BCD value in 100 mV	11.5V
4Eh	9Ch	00C5h	V <sub>PP</sub> Supply Maximum Program/Erase voltage bit 7 to 4 HEX value in volts bit 3 to 0 BCD value in 100 mV	12.5V
4Fh	9Eh	0002h 0003h	Top/Bottom Boot Block Flag 02h = Bottom Boot device 03h = Top Boot device	_
50h	A0h	0000h	Program Suspend 00h = Not Supported 01h = Supported	_

**Table 26. Security Code Area** 

Add	Address		Description	
x16	x8	Data	Description	
61h	C3h, C2h	XXXX		
62h	C5h, C4h	XXXX	64 hituurigua daviaa numbar	
63h	C7h, C6h	XXXX	64 bit: unique device number	
64h	C9h, C8h	XXXX		

#### APPENDIX C. EXTENDED MEMORY BLOCK

The M29W640D has an extra block, the Extended Block, that can be accessed using a dedicated command.

This Extended Block is 32 KWords in x16 mode and 64 KBytes in x8 mode. It is used as a security block (to provide a permanent security identification number) or to store additional information.

The Extended Block is either Factory Locked or Customer Lockable, its status is indicated by bit DQ7. This bit is permanently set to either '1' or '0' at the factory and cannot be changed. When set to '1', it indicates that the device is factory locked and the Extended Block is protected. When set to '0', it indicates that the device is customer lockable and the Extended Block is unprotected. Bit DQ7 being permanently locked to either '1' or '0' is another security feature which ensures that a customer lockable device cannot be used instead of a factory locked one.

Bit DQ7 is the most significant bit in the Extended Block Verify Code and a specific procedure must be followed to read it. See "Extended Memory Block Verify Code" in Tables 2 and 3, Bus Operations, BYTE =  $V_{IL}$  and Bus Operations, BYTE =  $V_{IH}$ , respectively, for details of how to read bit DQ7.

The Extended Block can only be accessed when the device is in Extended Block mode. For details of how the Extended Block mode is entered and exited, refer to the Enter Extended Block Command and Exit Extended Block Command paragraphs, and to Tables 4 and 5, "Commands, 16-bit mode, BYTE =  $V_{IH}$ " and "Commands, 8-bit mode, BYTE =  $V_{II}$ ", respectively.

### **Factory Locked Extended Block**

In devices where the Extended Block is factory locked, the Security Identification Number is written to the Extended Block address space (see Table 27, Extended Block Address and Data) in the factory. The DQ7 bit is set to '1' and the Extended Block cannot be unprotected.

#### **Customer Lockable Extended Block**

A device where the Extended Block is customer lockable is delivered with the DQ7 bit set to '0' and the Extended Block unprotected. It is up to the customer to program and protect the Extended Block but care must be taken because the protection of the Extended Block is not reversible.

There are two ways of protecting the Extended Block:

- Issue the Enter Extended Block command to place the device in Extended Block mode, then use the In-System Technique with RP either at V<sub>IH</sub> or at V<sub>ID</sub> (refer to Appendix D, In-System Technique and to the corresponding flowcharts, Figures 18 and 19, for a detailed explanation of the technique).
- Issue the Enter Extended Block command to place the device in Extended Block mode, then use the Programmer Technique (refer to Appendix D, Programmer Technique and to the corresponding flowcharts, Figures 16 and 17, for a detailed explanation of the technique).

Once the Extended Block is programmed and protected, the Exit Extended Block command must be issued to exit the Extended Block mode and return the device to Read mode.

Table 27. Extended Block Address and Data

Device	Addr	ess <sup>(1)</sup>	Data		
Device	x8	x16	Factory Locked	Customer Lockable	
M29W640DT	7F0000h-7F000Fh	3F8000h-3F8007h	Security Identification Number Determined Custome		
	7F0010h-7FFFFFh	3F8008h-3FFFFFh	Unavailable	Customer	
M29W640DB	000000h-00000Fh	000000h-000007h	Security Identification Number	Determined by Customer	
	000010h-00FFFFh	000008h-007FFFh	Unavailable	Customer	

Note: 1. See Tables 19 and 20, Top and Bottom Boot Block Addresses.



### APPENDIX D. BLOCK PROTECTION

Block protection can be used to prevent any operation from modifying the data stored in the memory. The blocks are protected in groups, refer to Appendix A, Table 19 and Table 20 for details of the Protection Groups. Once protected, Program and Erase operations within the protected group fail to change the data.

There are three techniques that can be used to control Block Protection, these are the Programmer technique, the In-System technique and Temporary Unprotection. Temporary Unprotection is controlled by the Reset/Block Temporary Unprotection pin, RP; this is described in the Signal Descriptions section.

## **Programmer Technique**

The Programmer technique uses high  $(V_{ID})$  voltage levels on some of the bus pins. These cannot be achieved using a standard microprocessor bus, therefore the technique is recommended only for use in Programming Equipment.

To protect a group of blocks follow the flowchart in Figure 16, Programmer Equipment Group Protect Flowchart. To unprotect the whole chip it is necessary to protect all of the groups first, then all groups can be unprotected at the same time. To unprotect the chip follow Figure 17, Programmer Equipment Chip Unprotect Flowchart. Table 28, Programmer Technique Bus Operations, BYTE =  $V_{IH}$  or  $V_{IL}$ , gives a summary of each operation.

The timing on these flowcharts is critical. Care should be taken to ensure that, where a pause is

specified, it is followed as closely as possible. Do not abort the procedure before reaching the end. Chip Unprotect can take several seconds and a user message should be provided to show that the operation is progressing.

### In-System Technique

The In-System technique requires a high voltage level on the Reset/Blocks Temporary Unprotect pin, RP<sup>(1)</sup>. This can be achieved without violating the maximum ratings of the components on the microprocessor bus, therefore this technique is suitable for use after the memory has been fitted to the system.

To protect a group of blocks follow the flowchart in Figure 18, In-System Equipment Group Protect Flowchart. To unprotect the whole chip it is necessary to protect all of the groups first, then all the groups can be unprotected at the same time. To unprotect the chip follow Figure 19, In-System Equipment Chip Unprotect Flowchart.

The timing on these flowcharts is critical. Care should be taken to ensure that, where a pause is specified, it is followed as closely as possible. Do not allow the microprocessor to service interrupts that will upset the timing and do not abort the procedure before reaching the end. Chip Unprotect can take several seconds and a user message should be provided to show that the operation is progressing.

Note: 1.  $\overline{RP}$  can be either at  $V_{IH}$  or at  $V_{ID}$  when using the In-System Technique to protect the Extended Block.

Table 28. Programmer Technique Bus Operations, BYTE = VIH or VIL

Operation	Ē	IG	$\overline{w}$	Address Inputs A0-A21	Data Inputs/Outputs DQ15A-1, DQ14-DQ0
Block (Group) Protect <sup>(1)</sup>	V <sub>IL</sub>	V <sub>ID</sub>	V <sub>IL</sub> Pulse	A9 = V <sub>ID</sub> , A12-A21 Block Address Others = X	Х
Chip Unprotect	V <sub>ID</sub>	V <sub>ID</sub>	V <sub>IL</sub> Pulse	$A9 = V_{ID}, A12 = V_{IH}, A15 = V_{IH}$ $Others = X$	Х
Block (Group) Protection Verify	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	$\begin{array}{c} \text{A0 = V}_{\text{IL}},\text{A1 = V}_{\text{IH}},\text{A6 = V}_{\text{IL}},\text{A9 = V}_{\text{ID}},\\ \text{A12-A21 Block Address}\\ \text{Others = X} \end{array}$	Pass = XX01h Retry = XX00h
Block (Group) Unprotection Verify	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	$A0 = V_{IL}, A1 = V_{IH}, A6 = V_{IH}, A9 = V_{ID},$ $A12\text{-}A21 \ Block \ Address}$ $Others = X$	Retry = XX01h Pass = XX00h

Note: 1. Block Protection Groups are shown in Appendix A, Tables 19 and 20.

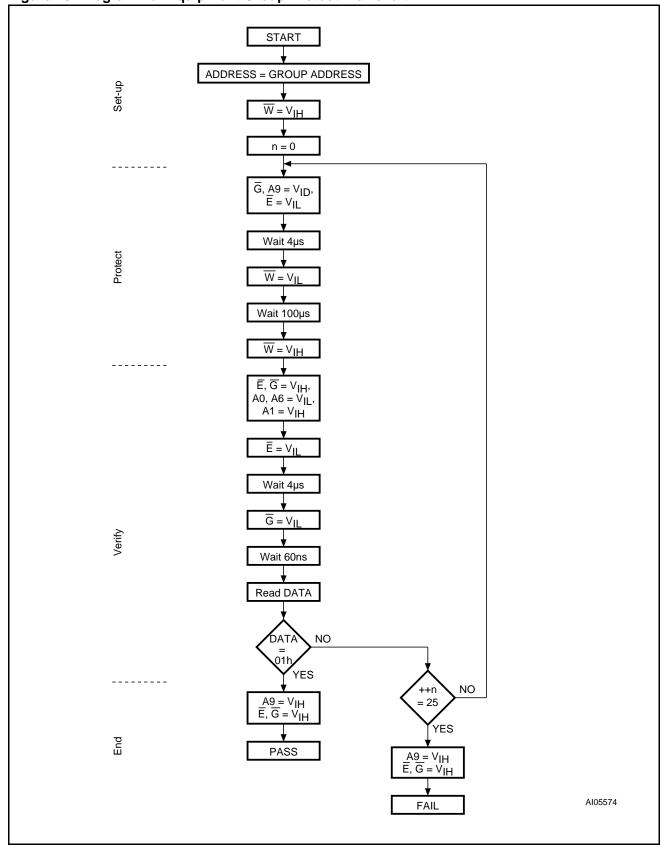


Figure 16. Programmer Equipment Group Protect Flowchart

Note: Block Protection Groups are shown in Appendix D, Table 19 and Table 20.



**START** PROTECT ALL GROUPS Set-up n = 0CURRENT GROUP = 0 A6, A12, A15 = V<sub>IH</sub><sup>(1)</sup> E, G, A9 = V<sub>ID</sub> Wait 4µs  $\overline{W} = V_{II}$ Wait 10ms  $\overline{W} = V_{IH}$  $\overline{E}$ ,  $\overline{G}$  =  $V_{IH}$ ADDRESS = CURRENT GROUP ADDRESS  $A0 = V_{IL}, A1, A6 = V_{IH}$  $\bar{\mathsf{E}} = \mathsf{V}_{\mathsf{IL}}$ Wait 4µs  $\overline{G} = V_{II}$ INCREMENT **CURRENT GROUP** Wait 60ns Verify Read DATA DATA YES NO LAST NO GROUP 1000 YES YES A9 = V<sub>IH</sub>  $A9 = V_{IH}$ E, G =  $V_{IH}$  $\overline{E}$ ,  $\overline{G}$  =  $V_{IH}$ End FAIL **PASS** AI05575

Figure 17. Programmer Equipment Chip Unprotect Flowchart

Note: Block Protection Groups are shown in Appendix D, Table 19 and Table 20.

47/

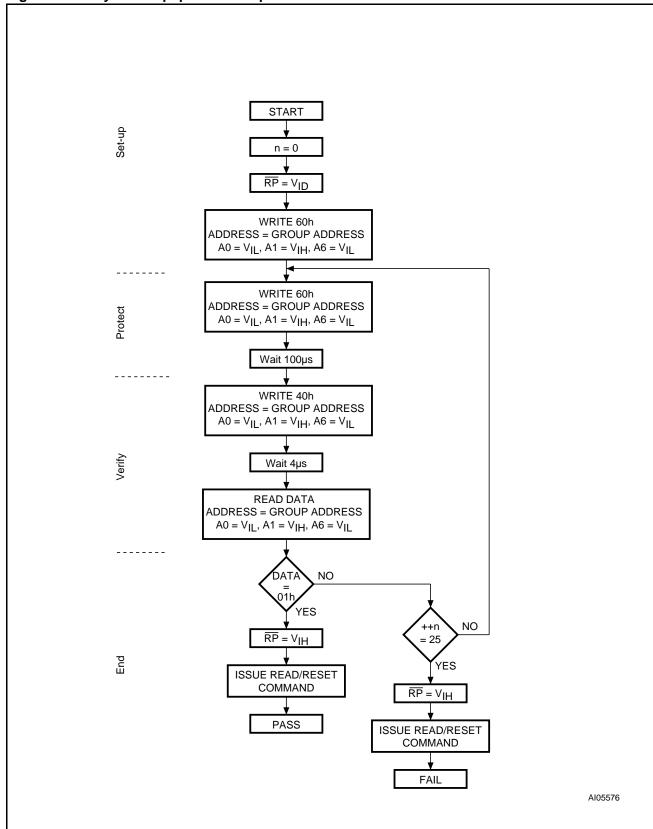


Figure 18. In-System Equipment Group Protect Flowchart

Note: 1. Block Protection Groups are shown in Appendix D, Table 19 and Table 20.

2.  $\overline{RP}$  can be either at  $V_{IH}$  or at  $V_{ID}$  when using the In-System Technique to protect the Extended Block.



START PROTECT ALL GROUPS n = 0CURRENT GROUP = 0  $\overline{\mathsf{RP}} = \mathsf{V}_{\mathsf{ID}}$ WRITE 60h ANY ADDRESS WITH  $A0 = V_{IL}, A1 = V_{IH}, A6 = V_{IH}$ WRITE 60h ANY ADDRESS WITH  $\mathsf{A0} = \mathsf{V}_{\mathsf{IL}},\, \mathsf{A1} = \mathsf{V}_{\mathsf{IH}},\, \mathsf{A6} = \mathsf{V}_{\mathsf{IH}}$ Wait 10ms WRITE 40h ADDRESS = CURRENT GROUP ADDRESS  $\mathsf{A0} = \mathsf{V}_{\mathsf{IL}},\, \mathsf{A1} = \mathsf{V}_{\mathsf{IH}},\, \mathsf{A6} = \mathsf{V}_{\mathsf{IH}}$ Wait 4µs **INCREMENT CURRENT GROUP READ DATA** ADDRESS = CURRENT GROUP ADDRESS  $A0 = V_{IL}, A1 = V_{IH}, A6 = V_{IH}$ DATA YES AST NO = 1000 GROUP YES YES RP = V<sub>IH</sub>  $\overline{RP} = V_{IH}$ ISSUE READ/RESET ISSUE READ/RESET COMMAND COMMAND **PASS FAIL** AI05577

Figure 19. In-System Equipment Chip Unprotect Flowchart

Note: Block Protection Groups are shown in Appendix D, Table 19 and Table 20.

7/

# **REVISION HISTORY**

**Table 29. Document Revision History** 

Date	Version	Revision Details
14-Dec-2001	-01	Document released
19-Apr-2002	-02	Description of Ready/Busy signal clarified (and Figure 12 modified) Clarified allowable commands during Block Erase Clarified the mode the device returns to in the CFI Read Query command section tPLYH (time to reset device) respecified. Correction to table of Commands.
24-Apr-2002	-03	Values for addresses 23h and 25h corrected in CFI Query System Interface Information table in Appendix B
05-Sep-2002	3.1	When in Extended Block mode, the block at the boot block address can be used as OTP. Value of electronic signature changed. Data Toggle Flow chart corrected. SO44 package removed. Double Word Program Time (typ) changed to 20s. Revision numbering modified: a minor revision will be indicated by incrementing the digit after the dot, and a major revision, by incrementing the digit before the dot (revision version 03 equals 3.0).
08-Jan-2003	3.2	Values corrected for typical times for Double Word Program (Byte or Word) and Chip Program (Quadruple Byte, Double Word) in the Program, Erase Times and Program, Erase Endurance Cycles table.  Document promoted from Product Preview to Preliminary Data.
04-Apr-2003	3.3	Data Retention and Erase Suspend Latency Time parameters added to Table 6, Program, Erase Times and Program, Erase Endurance Cycles, and Typical after 100k W/E Cycles column removed. I $_{\rm ID}$ (Identification) current removed from Table 11, DC Characteristics. Data modified at addresses 2Eh, 31h, 32h in Table 24. Extended Memory Block Verify Codes modified in Tables 2 and 3, "Bus Operations, BYTE = $V_{\rm IL}$ " and "Bus Operations, BYTE = $V_{\rm IH}$ ", respectively. Block 75 address space corrected for x8 mode in Table 19, Top Boot Block Addresses, M29W640DT, and Block 71 address space corrected for x8 mode in Table 20, Bottom Boot Block Addresses, M29W640DB. Appendix C, EXTENDED MEMORY BLOCK, added. $V_{\rm SS}$ pin connection to ground clarified. Lead-free package options E and F added to Table 18, Ordering Information Scheme.
2-Oct-2003	3.4	Status of Ready/Busy signal for Erase Suspend Operation modified in Table 7, Status Register Bits.  Double Word Program Command modified in COMMAND INTERFACE section.  TLEAD parameter added in Table 8, Absolute Maximum Ratings.  Note modified and addresses 31h to 3Ch added in Table 24, Device Geometry Definition.  Addresses 43h and 4Eh modified; addresses 4Fh and 50h added in Table 25, Primary Algorithm-Specific Extended Query Table.
10-Nov-2003	3.5	70ns access time option removed.
19-Dec-2003	3.6	V <sub>PP</sub> and I <sub>PP</sub> test conditions updated in Table 11, DC Characteristics. Block Protect/Unprotect code updated in Appendix B, Table 25. Customer Lockable Extended Block mechanism modified in Appendix C, Extended Memory Block. Appendix D, Block Protection updated: Note 1 added in the In-System Technique section and Note 2 added below Figure 18, In-System Equipment Group Protect Flowchart.



Information furnished is believed to be accurate and reliable. However, STMicroelectronics assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of STMicroelectronics. Specifications mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. STMicroelectronics products are not authorized for use as critical components in life support devices or systems without express written approval of STMicroelectronics.

The ST logo is a registered trademark of STMicroelectronics.

All other names are the property of their respective owners.

© 2003 STMicroelectronics - All rights reserved

STMicroelectronics GROUP OF COMPANIES

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States

www.st.com

